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HARRY DIAMOND LABS ADELPHI MD
SEMCON: A SEMICONDUCTOR DAMAGE DATA REDUCTION COMPUTER CODE.(U)

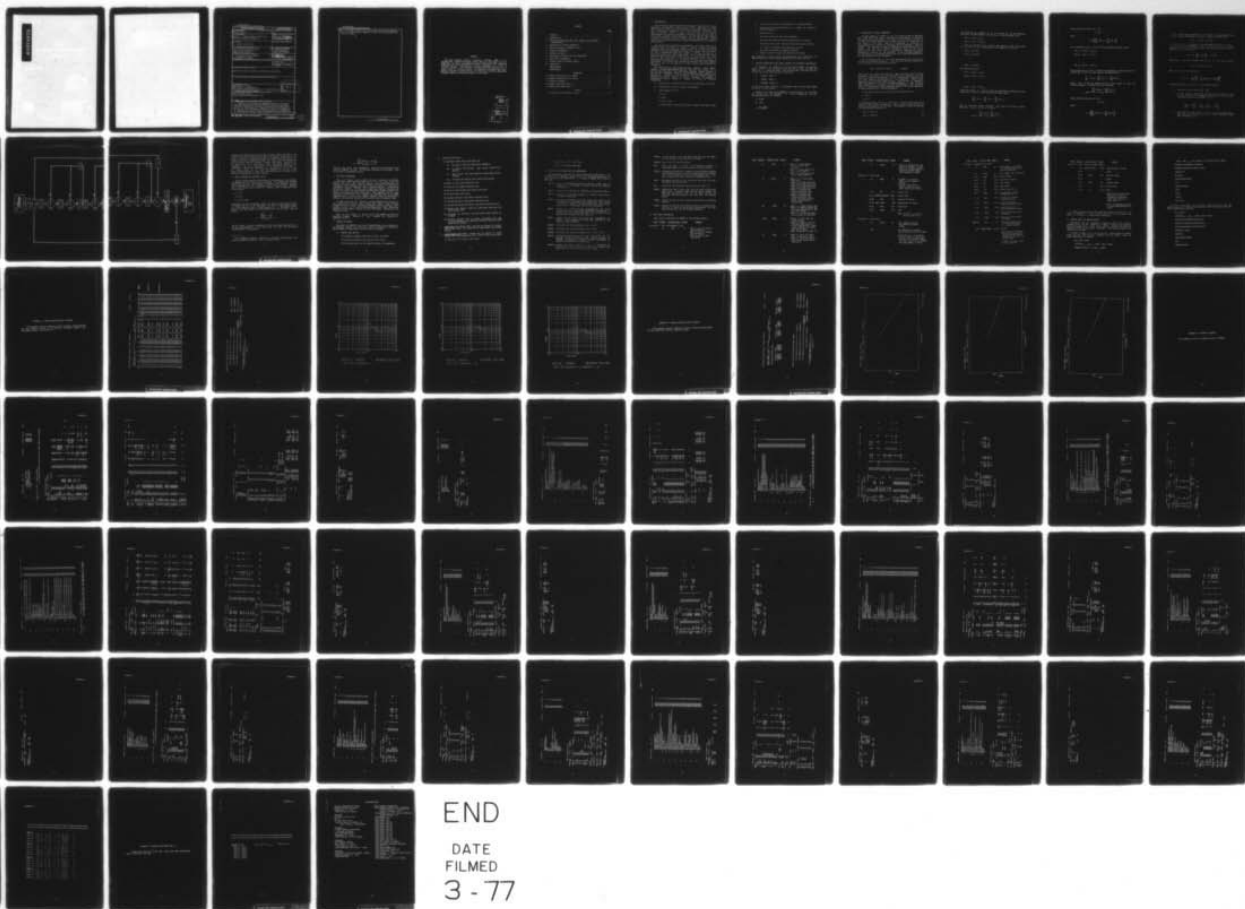
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plots of least-squares fits. This report details the development and capabilities of SEMCON, as well as the procedures for using the code.

FOREWORD

The Army Multiple Systems Evaluation Program (MSEP) is a comprehensive program developing general analytic techniques for the prediction of high electromagnetic-pulse vulnerability and hardening technology and for the application of these techniques to a list of critical systems. The analytic techniques have been verified for a large class of tactical systems. The hardening techniques have been applied to specific systems and are now resulting in product improvement programs leading to hardened equipment in the field.

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1. INTRODUCTION

This effort was written under the sponsorship of the Multiple Systems Evaluation Program (MSEP), which has as its main objective to harden Army tactical systems to the electromagnetic pulse (EMP) associated with the exoatmospheric detonation of a nuclear weapon. Along with this major objective, MSEP is tasked also with the aim to develop experimental and analytical evaluation techniques that are applicable to all systems' problems. These objectives are satisfied, since SEMCON provides an analytic method to examine various semiconductor devices used in Army systems and assists in making recommendations for hardening modifications.

When making EMP vulnerability assessments, it is often necessary to perform a circuit analysis on specific circuits driven by a voltage induced by EMP. This analysis often points out a large power value produced on various semiconductor devices that could cause the devices to fail if sufficient power were present. However, to know if a particular device fails and at what power level, a semiconductor device must be analyzed and a damage curve fitted to certain data. This curve gives a good indication as to the vulnerability of the device to particular thresholds of power. Therefore, the main purpose of computer code SEMCON is to provide the necessary information about semiconductor devices so that it is possible to make various EMP vulnerability assessments.

The semiconductor damage-data-reduction computer code, SEMCON, analyzes various semiconductor devices. The code was written for a Control Data Corporation (CDC) 6600 series computer system located at the Mobility Equipment Research and Development Center (MERDC), Fort Belvoir, VA. Written to run employing the FTN compiler, SEMCON is operational using the SCOPE 3.4.3 control language. To evaluate a semiconductor device, SEMCON is capable of giving the following information:

- a. Determination of damage--the failure or nonfailure of a device
- b. Calculations of power, energy, and impedance
- c. Least-squares fits of

$$p = at^{-1},$$

$$p = bt^{-\frac{1}{2}},$$

$$p = at^{-1} + bt^{-\frac{1}{2}}$$

to either power versus failure time or power versus pulse width

- d. Selection of the best least-squares fit to specified data
- e. Log-log plots of least-squares fits in either the forward or reverse direction
- f. Log-log plots of
 - TD versus Z--failure time versus impedance
 - TD versus VOC--failure time versus open-circuit voltage
 - TDOC versus VOC--pulse duration versus open-circuit voltage
 - TD versus IP--failure time versus peak current
 - in either the forward or reverse direction
- g. Tabular listing of input data and all calculations

The subsequent sections detail the development and capabilities of SEMCON, along with the necessary information to utilize the code.

2. FAILURE DETERMINATION AND POWER, ENERGY, AND IMPEDANCE CALCULATIONS

To determine the damage on a particular pulse number, the specific values used in the calculations are (1) VZBP and VZAP, (2) VZBN and VZAN, and (3) GAINB and GAINA. The criteria used to determine failure are any one of the following three conditions:

- a. $.8 * VZBP - VZAP > 0$
- b. $.8 * VZBN - VZAN > 0$
- c. $.8 * GAINB - GAINA > 0$

If any one of these conditions is satisfied, then for that pulse number the device is said to fail.

Another of the features of SEMCON is the calculations of the power (P), energy (E), and impedance (Z). These computations are very straightforward and are found by

$$P = VP * TD,$$

$$E = P * TD,$$

$$Z = \frac{VP - VZBP}{IP}.$$

3. DERIVATION OF FITTING PARAMETERS

The main purpose of SEMCON is to fit various curves to specified data. They are fit by using the method of least squares to calculate the various fitting parameters. The plots of these curves, as well as the data, are scaled logarithmically, since there can be a wide range in the values of the data. Thus, it is necessary to calculate the least-squares fits in terms of logarithms, which introduces a nonlinear problem. Two methods are used to calculate the least-squares fits in SEMCON. One uses the minimizing conditions known as the normal equations, and the other uses a minimization technique to find the minimum of a function of two variables. In the following paragraphs, the two methods are explained fully along with a detailed derivation of the least-squares fitting parameters.

The first method used to find the least-squares fits involves the solution of the normal equations. This technique involves substituting the n data pairs into the fitting equation.

$$f(x) = a_1\phi_1(x) + a_2\phi_2(x) + \dots + a_k\phi_k(x),$$

where $\phi_i(x)$ are known functions of x , and a_i are the k linear fitting parameters, thus obtaining n linear equations with k unknowns. The next step is to multiply each equation by its corresponding coefficient of the first unknown, which results in n new equations. Adding these equations gives the first normal equation. This process is repeated k times with respect to each of the unknown parameters, so that we end up with k equations in k unknowns (the fitting parameters). The resulting system of simultaneous linear equations, known as the normal equations, is then solved for the k fitting parameters.

In our particular case, we wish to use this method to fit

$$p = at^{-1},$$

$$p = bt^{-\frac{1}{2}}$$

to experimental data, where p is the power, t is the failure time, and a and b are the fitting parameters. Since plots are desired that are scaled logarithmically, we must find the parameters a and b by applying the least-squares technique to

$$\log p = \log at^{-1}, \tag{1}$$

$$\log p = \log bt^{-\frac{1}{2}}. \tag{2}$$

All logarithms are assumed to be to the base 10. By the elementary properties of logarithms, we clearly have a linear problem, since

$$\log p = \log a - \log t,$$

$$\log p = \log b - \frac{1}{2} \log t.$$

First, we consider $\log p = \log at^{-1}$ and suppose we have n data pairs (t_i, p_i) for $1 \leq i \leq n$. Substituting into equation (1), we get

$$\log p_1 = \log at_1^{-1},$$

$$\log p_2 = \log at_2^{-1},$$

.

$$\log p_n = \log at_n^{-1},$$

and simplifying gives

$$\log p_1 = \log a - \log t_1,$$

$$\log p_2 = \log a - \log t_2,$$

.

$$\log p_n = \log a - \log t_n.$$

Since this system is linear in terms of logarithms, multiplying by the coefficient of $\log a$ in each equation and adding gives

$$\sum_{i=1}^n \log p_i = \sum_{i=1}^n \log a - \sum_{i=1}^n \log t_i.$$

This is the only normal equation, since there is only one fitting parameter. Solving for $\log a$, we obtain

$$\log a = \frac{\sum_{i=1}^n \log p_i + \sum_{i=1}^n \log t_i}{n},$$

which gives the solution for a as

$$a = 10^x ,$$

where

$$x = \frac{1}{n} \left(\sum_{i=1}^n \log p_i + \sum_{i=1}^n \log t_i \right).$$

Now, considering $\log p = \log b t^{-\frac{1}{2}}$ and proceeding as above, we get

$$\log p_1 = \log b - \frac{1}{2} \log t_1 ,$$

$$\log p_2 = \log b - \frac{1}{2} \log t_2 ,$$

.

$$\log p_n = \log b - \frac{1}{2} \log t_n .$$

This system also is linear in terms of logarithms, so multiplying by the coefficient of $\log b$ in each equation and adding gives

$$\sum_{i=1}^n \log p_i = \sum_{i=1}^n \log b - \frac{1}{2} \sum_{i=1}^n \log t_i .$$

Again, this is the only normal equation, since there is only one fitting parameter. Solving for $\log b$, we obtain

$$\log b = \frac{\sum_{i=1}^n \log p_i + \frac{1}{2} \sum_{i=1}^n \log t_i}{n} ,$$

which gives the solution for b as

$$b = 10^y ,$$

where

$$y = \frac{1}{n} \left(\sum_{i=1}^n \log p_i + \frac{1}{2} \sum_{i=1}^n \log t_i \right) .$$

The second method employed to calculate the least-squares fits involves finding a minimum of a function. Suppose we want to fit

$$f(x) = a_1\phi_1(x) + a_2\phi_2(x)$$

to n data points, where $\phi_1(x)$, $\phi_2(x)$ are known functions of x , and a_1 , a_2 are the fitting parameters. Let $\bar{f}_i = \bar{f}(x_i)$ for $1 \leq i \leq n$ be the experimental data that we wish to fit. Then by the principle of least squares, we want to minimize

$$F(a_1, a_2) = \sum_{i=1}^n w(x_i) \left[\bar{f}_i - f(x_i) \right]^2,$$

where $w(x_i)$ is the weight function for each x_i . For our case, we choose

$$w(x_i) = 1 \text{ for } 1 \leq i \leq n.$$

Thus, we must find the minimum of

$$F(a_1, a_2) = \sum_{i=1}^n \left\{ \bar{f}_i - \left[a_1\phi_1(x_i) + a_2\phi_2(x_i) \right] \right\}^2.$$

To find the minimum, we proceed in the following manner:

- a. Start with initial values $a_1^{(0)}$, $a_2^{(0)}$.
- b. At the i th step, halve $a_1^{(i)}$, and try to step first in the positive and then in the negative x -direction, to see if either resulting value gives a minimum, i.e.,

$$F\left[a_1^{(i)} \pm \frac{a_1^{(i)}}{2^j}, a_2^{(i)}\right] < F\left[a_1^{(i)}, a_2^{(i)}\right].$$

- c. Halve $a_2^{(i)}$, and try to step first in the positive and then in the negative y -direction, to see if either resulting value gives a minimum, i.e.,

$$F\left[a_1^{(i)}, a_2^{(i)} \pm \frac{a_2^{(i)}}{2^j}\right] < F\left[a_1^{(i)}, a_2^{(i)}\right].$$

d. If neither (b) nor (c) gives a minimum halve $a_1^{(i)}$ and $a_2^{(i)}$ again, and repeat (b) and (c), i.e., $j = 2$.

e. If a minimum results from either (b) or (c), then let

$$a_1^{(i+1)} = a_1^{(i)} \pm \frac{a_1^{(i)}}{2^j}, \quad a_2^{(i+1)} = a_2^{(i)}, \quad \text{if only (b) holds,}$$

$$a_2^{(i+1)} = a_2^{(i)} \pm \frac{a_2^{(i)}}{2^j}, \quad a_1^{(i+1)} = a_1^{(i)}, \quad \text{if only (c) holds,}$$

$$a_1^{(i+1)} = a_1^{(i)} \pm \frac{a_1^{(i)}}{2^j}, \quad a_2^{(i+1)} = a_2^{(i)} \pm \frac{a_2^{(i)}}{2^j}, \quad \text{if (b) and (c) hold,}$$

and check

$$\left| F\left[a_1^{(i+1)}, a_2^{(i+1)}\right] - F\left[a_1^{(i)}, a_2^{(i)}\right] \right| < \epsilon, \quad (3) \quad (3)$$

where ϵ is a chosen convergence tolerance. If equation (3) holds, then

$$a_1 = a_1^{(i+1)}, \quad a_2 = a_2^{(i+1)}$$

are the fitting parameters. If equation (3) does not hold, the process is repeated.

This technique is very simple and always leads to a minimum although it may be only a local minimum. If a local minimum is reached which is not close to the true minimum, then it seems reasonable to assume that the least-squares fit will be poor. Thus, when the fit is bad, it could probably be attributed to this distant local minimum, although there are other occurrences that could cause a bad fit. The

only solution to this problem is to try the minimization technique again with different initial values. A repetition of this process leads to the true minimum of the function $F(a_1, a_2)$. The above technique was limited to two fitting parameters, but it is an easy matter to extend this method to k parameters.

For our purpose, we wish to use this method to fit

$$p = at^{-1} + bt^{-\frac{1}{2}} \quad (4)$$

to experimental data (t_i, \bar{p}_i) for $1 \leq i \leq n$, where p is the power, t is the failure time, n is the number of data points, and a and b are the fitting parameters. This poses a nonlinear problem, since $\log(at^{-1} + bt^{-\frac{1}{2}})$ cannot be linearized as was $\log(at^{-1})$ and $\log(bt^{-\frac{1}{2}})$. This problem is easily overcome by using the minimization technique described above. Let

$$P(t; a, b) = \log(at^{-1} + bt^{-\frac{1}{2}}),$$

and we want to minimize

$$S(a, b) = \sum_{i=1}^n w(t_i) \left[\log \bar{p}_i - P(t_i; a, b) \right]^2,$$

where $w(t_i)$ is the weight function for each t_i . Since we choose

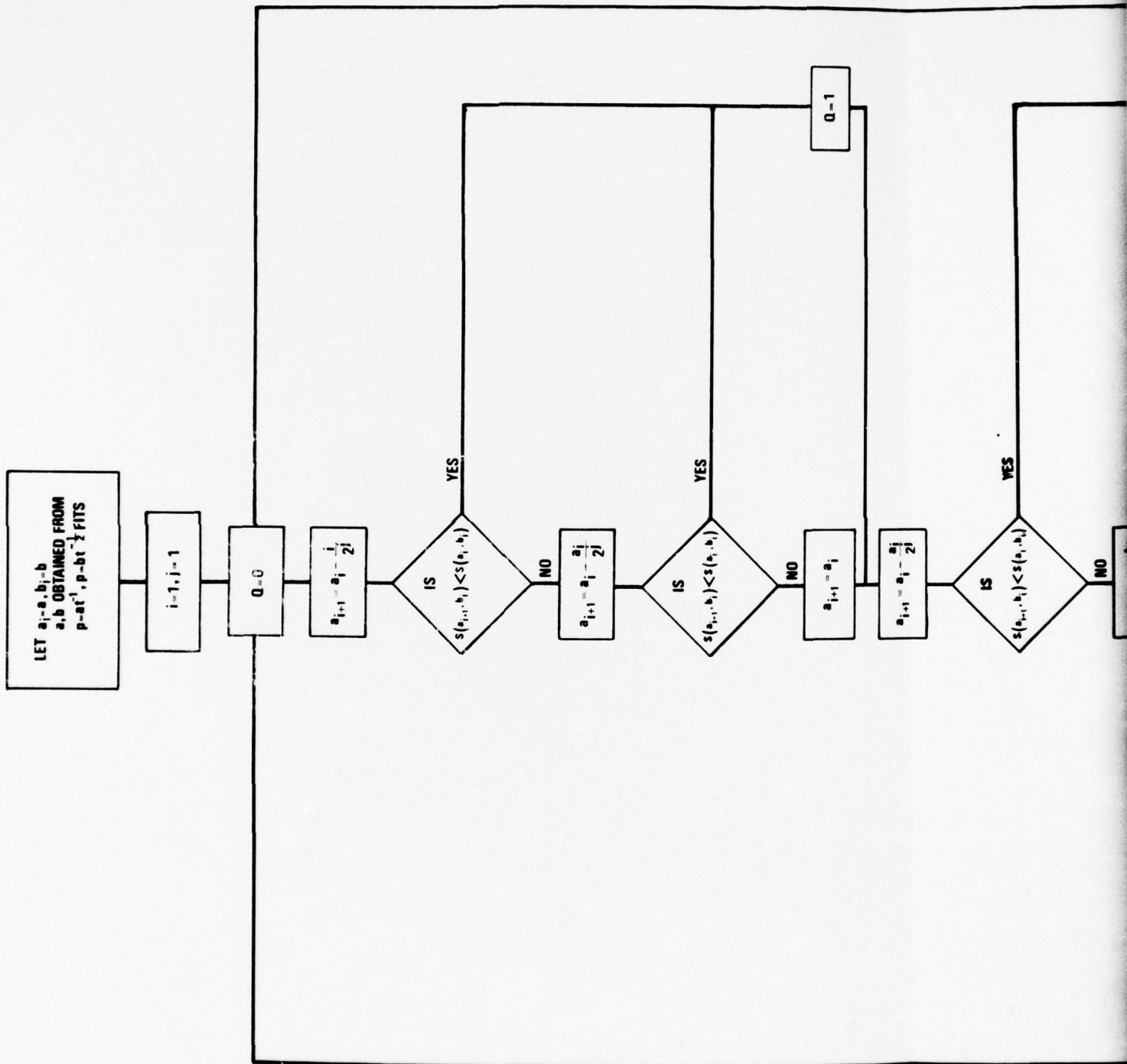
$$w(t_i) = 1 \quad \text{for } i = 1, 2, \dots, n,$$

we must minimize

$$S(a, b) = \sum_{i=1}^n \left[\log \bar{p}_i - \log(at_i^{-1} + bt_i^{-\frac{1}{2}}) \right]^2.$$

The minimization for $S(a, b)$ is identical to the minimization technique given above. A flow chart for finding the minimum of $S(a, b)$ and thus the fitting parameters a and b is given in figure 1.

Although the techniques outlined above are simple and straightforward, caution should be taken when interpreting the least-squares fits. First, the fits are only as good as the data. Poorly taken and recorded data result in meaningless fits. Probably the major fault with least squares is that a single very wrong measurement greatly distorts the results, because in the squaring process, large



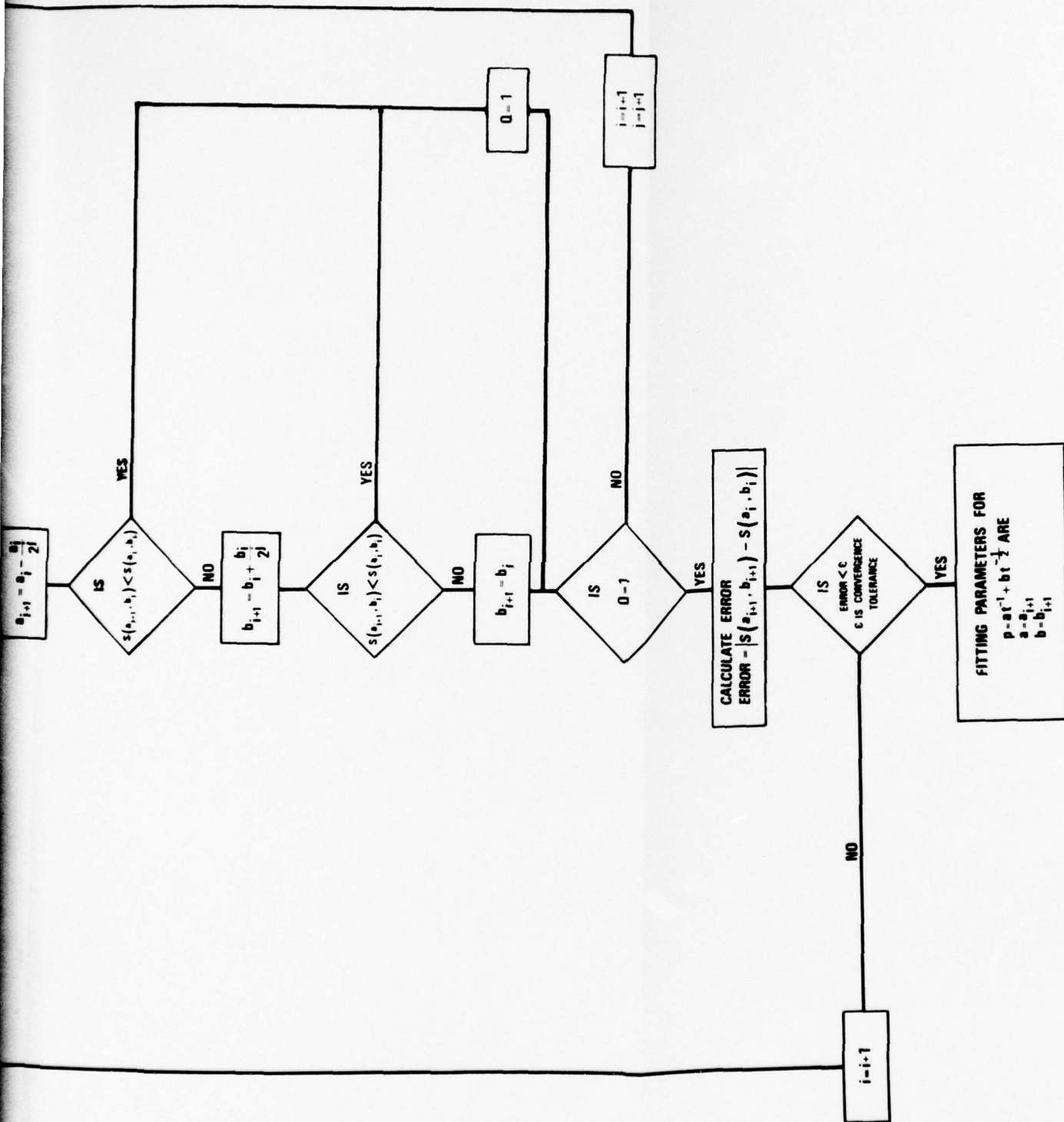


Figure 1. Flow chart for minimizing $S(a,b)$.

residuals are dominant--one gross error 10 times larger than most of the others has the same effect in the sum of the squares as have 100 of the others.¹ Second, a considerable amount of mathematical and statistical sophistication can be employed to give the fits much more reliability when the proper data are involved. Several statistical techniques can be applied to these least-squares fits that would enhance their assurance. One is a statistical test of hypothesis concerning the confidence in the fitting parameters a , b in equations (1), (2), and (4). The other would be to test the goodness of fit by using the χ^2 statistical test. These two techniques can be utilized to make SEMCON's least-squares fits more reliable.

4. GAUSS CRITERION OF GOODNESS OF FIT

One of the main questions pertaining to least-squares fits concerns the goodness of fit of the curve to the data. This problem can be dealt with when using the least-squares technique, and probably the most widely used method is the χ^2 goodness of fit statistical test. Although the χ^2 test has not been utilized in SEMCON, a test to determine which of the curves

$$p = at^{-1}$$

$$p = bt^{-1/2}$$

$$p = at^{-1} + bt^{-1/2}$$

best fits the data is applied. This test, known as the Gauss criterion of goodness of fit, is now explained. Let \bar{p}_i be an experimental value, p_i a value computed from a least-squares fit, n the number of data points, and m the number of fitting parameters in the relation. Then we define

$$\Omega = \frac{\sum_{i=1}^n (\bar{p}_i - p_i)^2}{n - m},$$

and the Gauss criterion of goodness of fit states that the best fit is the one that minimizes Ω . Since the plots of these fits are scaled logarithmically, we calculate

¹R. W. Hamming, *Numerical Methods for Scientists and Engineers*, 2nd edition, McGraw-Hill Book Co., Inc., New York (1973).

$$\Omega = \frac{\sum_{i=1}^n (\log \bar{p}_i - \log p_i)^2}{n - m}$$

and find the curve that minimizes Ω . Values of Ω are printed in the output of SEMCON, as well as the curve that best fits the data. This can be seen in appendices A and B.

5. PLOTTING INFORMATION

There are several ways to obtain the plots generated by SEMCON. Through MERDC, SEMCON has the capability to use a Cal Comp model 835 cathode ray tube (CRT) plotting system. This system takes plotting information from a magnetic tape and converts the data to be plotted to incremental plotter commands, which produce discrete, electron-beam deflections (relative to the x and y axes) and intensity variations on the face of a CRT. The CRT display is transmitted through a camera lens system and recorded on 35-mm microfilm. The exposed film is then processed, and the plots are recorded on a magnetic tape at the MERDC computer center. A call to the MERDC computer center is necessary to initiate the hard-copy processing of the plots from the magnetic tape.

In addition to the CRT plotting system, SEMCON has the ability to use a Mohawk Data Sciences (MDS) model 2400 remote batch terminal accompanied with a Houston Instruments COMLOT plotting system. This system, located at the Harry Diamond Laboratories (HDL) Woodbridge Research Facility (WRF), enables all plots and output information to be received on site.

Each of the methods to obtain plots from SEMCON has different plotting software. Examples of this software are contained in appendices A and B.

6. OPTIONS OF SEMCON

The output of SEMCON can be varied substantially, so an analysis of the possible options for outputting various information is essential. The following is a description of the options available.

a. Tabular data options

- (1) Listing of tabular data only--no plots are given.
- (2) Listings of tabular data and plots are given.
- (3) Plots are given, but the tabular listing is suppressed.

b. Plotting selections

(1) Available items versus item plots are

- (a) TD versus Z--failure time versus impedance
- (b) TD versus VOC--failure time versus open-circuit voltage
- (c) TDOC versus VOC--pulse duration versus open-circuit voltage
- (d) TD versus IP--failure time versus peak current.

(2) Plots in the reverse direction only

(3) Plots in the forward direction only

(4) Plots in both forward and reverse directions

(5) No item versus item plots

(6) Reverse direction item versus item plots only

(7) Forward direction item versus item plots only

(8) Forward and reverse direction item versus item plots only

(9) Forward and reverse direction item versus item plots and least-squares fits

(10) Plots may be received on the MDS remote batch terminal or at MERDC.

(11) Plotting software may be either the regular Cal Comp plotting software or the software available through the MDS remote batch terminal.

c. Input data--The regular input data may be entered or a simpler form of input data that requires only pulse width versus power entires.

d. Least-squares fits--Three curves may be fitted to either failure time (TD) versus power (P) or pulse width versus power.

- (1) Fit to $p = at^{-1}$ and $p = bt^{-\frac{1}{2}}$ only.

(2) Fit to $p = at^{-1} + bt^{-\frac{1}{2}}$ only.

(3) Fit to all three equations.

7. DESCRIPTION OF SEMCON AND ITS SUBROUTINES

The SEMCON code consists of a main program and 19 subroutines. The documentation of SEMCON is detailed by the following analysis of the main program and its subroutines. A listing of SEMCON can be found in appendix C.

SEMCON	reads in the data and writes the tabular output seen in appendix A. It also makes the power, energy, and impedance calculations.
FAILUR	calculates the failure or nonfailure of each pulse number.
FRFAIL	separates the data with respect to failure in the reverse or forward directions.
DIRECT	sets up the variables T and PP, which are used in the calculations of the three least-squares fits, with respect to either the forward or reverse direction. Also, DIRECT chooses which least-squares fit will be calculated.
WRITE	outputs the various fitting parameters for the chosen least-squares fit. Also, some other useful information is written, such as the curve that best fits the data and the minimum of the function $S(a,b)$ (sect. 4).
PLOTT	contains all the plot titles and axes information and labels. This subroutine initiates the plotting of all curves by calling PWRITE.
ALSQAR	calculates the fitting parameter for $p = at^{-1}$.
BLSQAR	calculates the fitting parameter for $p = bt^{-\frac{1}{2}}$.
ABLSQAR	calculates the fitting parameters for $p = at^{-1} + bt^{-\frac{1}{2}}$.
PWRITE	performs the plotting using the Cal Comp model 835 CRT plotting system by calling the WRF library routines in TALPLOT. The subroutines SELPLOT, TALGRAF, and TALDATA of TALPLOT are referenced in PWRITE only.
SELPLOT	selects the beam intensity of the Cal Comp model 835 microfilm plotter and also enables the user to choose if he wants the plots sent to the MDS system at WRF.

TALGRAF sets up the plot axes and labels and specifies the number of sets of data to be plotted on one graph.

TALDATA plots a set of (x,y) data pairs.

SORT sorts the data in array T of subroutine DIRECT in increasing order so that the plotting is done correctly.

GOODFIT calculates the sum of the squares of the difference between the experimental value and the corresponding value computed from a least-squares fit for each least-squares fit. This sum is used in the Gauss criterion of goodness of fit.

GAUSS Determines the best fit for the data by the Gauss criterion and outputs the correct fit.

SAB calculates the functional values of $S(a,b)$ (sect. 4).

OWNDAT enables the user to enter only data for pulse width versus power input. It outputs these data by calling COLMNS and makes the appropriate calls to the other routines to calculate the least-squares fits and make the desired plots.

COLMNS outputs the data for pulse width versus power in increasing columns.

CHANGE changes the abscissa and ordinate titles to correspond with the use of data for pulse width versus power. It also enters those data into the plotting software.

8. DATA INPUT PREPARATION

Input cards are prepared for SEMCON in the following manner.

<u>Card</u>	<u>Columns</u>	<u>Variable name</u>	<u>Format</u>	<u>Comment</u>
Card set 1: Plot and parameter card				
1	10	IND	I1	IND = 1, plot in reverse direction only IND = 2, plot in forward direction only IND = 3, plot in both directions

<u>Card</u>	<u>Columns</u>	<u>Variable name</u>	<u>Format</u>	<u>Comment</u>
1	20	FLAG	I1	<p>FLAG = 1, least-squares fit to $p = at^{-1}$ and $p = bt^{-1/2}$</p> <p>FLAG = 2, least-squares fit to $p = at^{-1} + bt^{-1/2}$</p> <p>FLAG = 3, least-squares fit to all three equations</p>
	30	IPRAM	I1	<p>IPRAM = 0, no item versus item plots</p> <p>IPRAM = 1, reverse direction item versus item plots only</p> <p>IPRAM = 2, forward direction item versus item plots only</p> <p>IPRAM = 3, forward and reverse direction item versus item plots only</p> <p>IPRAM = 4, forward and reverse direction item versus item plots and all curves as specified by IND and FLAG</p>
	40	ISTOP	I1	<p>ISTOP = 1, tabular output only</p> <p>ISTOP = 2, tabular output and all output designated by IND, FLAG, and IPARAM</p> <p>ISTOP = 3, no tabular output, but all plots as indicated</p>
	49-50	IPLLOT	I2	<p>IPLLOT = 0, plots come out on MDS system</p> <p>IPLLOT = K, where $1 < K < 36$ indicates beam intensity of Cal Comp plotter; a good value is IPLLOT = 18; plots come out at MERDC</p> <p>NOTE: ITYPE must be equal to 0.</p>
	60	ISEM	II	<p>ISEM = 0, enter all input data in card sets 3 and 4</p> <p>ISEM = 1, enter only pulse width versus power data on card set 5</p>

<u>Card</u>	<u>Columns</u>	<u>Variable name</u>	<u>Format</u>	<u>Comment</u>
1	70	ITYPE	II	ITYPE = 0, regular Cal Comp plotting software is used ITYPE = 1, plotting software available on MDS remote batch terminal is used

Card set 2: Title card

2	1-3	NUMB	I3	If ISEM = 0 on card 1, NUMB is total number of devices If ISEM = 1 on card 1, NUMB is number of pulse width versus power points
---	-----	------	----	--

	4-11	DEV	A8	Device name
--	------	-----	----	-------------

	12-31	DEVTYP1,DEVTYP2	2A10	Device type
--	-------	-----------------	------	-------------

	32-40	JUNC	A9	Junction of device
--	-------	------	----	--------------------

	41-60	MAN1, MAN2	2A10	Manufacturer of device
--	-------	------------	------	------------------------

	61-70	TECH	A10	Technician
--	-------	------	-----	------------

	71-80	DATEE	A10	Date
--	-------	-------	-----	------

NOTE: If ISEM = 1 on card 1,
skip to card set 5.

Card set 3: Pulse card

3	1-2	NPULS	I2	Total number of pulses for particular device number
---	-----	-------	----	---

	3-80	-	-	Any comments or notations may be placed in these columns
--	------	---	---	--

NOTE: Card set 3 is repeated as many times as indicated on card set 2 for variable NUMB, and thus card set 4 is repeated this same number of times.

<u>Card</u>	<u>Columns</u>	<u>Variable name</u>	<u>Format</u>	<u>Comment</u>
Card set 4: Parameter value cards				
4	1-3	NDEV	I3	Device number; total number of repetitions of this card must not exceed 600
	4-5	PULSE	I2	Pulse number; not to exceed 99
	6-15	TDOC	E10.3	Pulse duration
	16-25	VOC	F10.3	Open-circuit voltage
	26-35	VP	F10.3	Peak voltage
	36-45	IP	F10.3	Peak current
	46-55	TD	E10.3	Failure time (TD \neq 0)
	56-65	VZBP	F10.3	Voltage before forward breakdown voltage
	5	1-10	VZAP	F10.3 Voltage after forward breakdown voltage
		11-20	VZBN	F10.3 Zener voltage before reverse breakdown voltage
		21-30	VZAN	F10.3 Zener voltage after reverse breakdown voltage
		31-40	GAINB	E10.3 Current gain before device was pulsed
		41-50	GAINA	E10.3 Current gain after device was pulsed
	51-52	PIN	A2	Polarity of applied pulse: A+ = forward direction C+ = reverse direction
	53-71	REMAR1, REMAR2	A10, A9	Remarks

NOTE: Card set 4 represents data for one pulse and is repeated as many times as indicated on card set 3 for variable NPULS.

If ISEM = 0 on Card 1, data input is complete

<u>Card</u>	<u>Columns</u>	<u>Variable name</u>	<u>Format</u>	<u>Comment</u>
Card set 5: Pulse width and power cards				
6	1-20	IDENT1,IDENT2	2A10	Identification of data
	21-30	-	-	Blank
	31-40	XLAB	A10	Abscissa label
	41-50	-	-	Blank
	51-60	YLAB	A10	Ordinate label
7	1-10	T	E10.3	Pulse width
	11-20	PP	E10.3	Power

NOTE: Data for pulse width versus power must be arranged in increasing order with respect to pulse width.

Card 7 is repeated according to value NUMB appearing on Card 2

A sample listing of the input cards when ISEM = 0 on card set 1 is given in appendix D. Also, a sample listing of the input cards when ISEM = 1 on card set 1 is contained in appendix E.

9. CONTROL CARDS FOR RUNNING SEMCON

The SEMCON code is operational using the SCOPE 3.4.3 control language on the CDC 6600 computer at MERDC. Since several different plotting packages can be used, three distinct control card sets are required for the various options available. The following details the operation of the code.

If IPLOT = K where $1 \leq K \leq 36$ on card set 1 (plots come out at MERDC using the Cal Comp plotting software), then the control cards for running SEMCON are as follows:

```
EM___(MT1, T300)

TASK(TNEM____,PW____,TRTS) [user's name]

REQUEST, TAPE50, HI, VSN=____,RING.
```

NOTE: VSN=___ is the number of the blank tape at MERDC.

ATTACH,AGO,BINSEMCON,ID=EM71606.

ATTACH,F1,TALWYATT,ID=EM71602,MR=1.

LIBRARY(F1)

MAP(PART)

LDSET(PRESET=NGINF)

AGO.

TALPLOT(,TAPE1)

EXIT.

7/8/9

[Data]

0/6/7/8/9

If IPLOT = 0 and ITYPE = 0 on card set 1 (plots come out on the MDS system using the Cal Comp plotting software), then the control cards for running SEMCON are as follows:

EM___(T300)

TASK(TNEM____,PW____,TRTS) [user's name]

ATTACH,AGO,BINSEMCON,ID=EM71606.

ATTACH,F1,TALWYATT,ID=EM71602,MR=1.

ATTACH,LIBA,ANAPAC,ID=EM71605,MR=1.

LIBRARY(F1,LIBA)

MAP(PART)

LDSET(PRESET=NGINF)

AGO.

TALPLOT(,TAPE1)

EXIT.

7/8/9

[Data]

0/6/7/8/9

If IPLOT = 0 and ITYPE = 1 on card set 1 (plots come out on the MDS system using the ANAPAC plotting software), then the control cards for running SEMCON are as follows:

EM___(T300)

TASK(TNEM_____,PW_____,TRTS) [user's name]

ATTACH,AGO,BINSEMCON,ID=EM71606.

ATTACH,LIBA,ANAPAC,ID=EM71605,MR=1.

LIBRARY(LIBA)

MAP(PART)

LDSET(PRESET=NGINF)

AGO.

EXIT.

7/8/9

[Data]

0/6/7/8/9

10. CONCLUSIONS

The SEMCON code has provided the means to analyze various semiconductor devices and, hence, assist in making EMP vulnerability assessments. The code has accomplished this objective by utilizing very straightforward techniques to calculate the least-squares fits for damage curves of semiconductor devices. For EMP efforts, the fits generated by SEMCON are considered to be reliable when good, accurate data are used. Also, the code has proven to be quite effective in tabulating and reducing numerous amounts of data. Thus, SEMCON is considered to be a useful code in semiconductor damage analysis and is written in such a way as to make it readily adaptable to numerous computer systems.

ABBREVIATIONS

E	Energy
FAIL	Failure
GAINA	Current gain after device was pulsed
GAINB	Current gain before device was pulsed
IP	Peak current
NDEV	Device number
P	Power
PIN	Polarity of applied pulse (i.e., reverse or forward direction)
PULSE	Pulse number
TD	Failure time
TDOC	Pulse duration
VOC	Open-circuit voltage
VP	Peak voltage
VZAN	Zener voltage after reverse breakdown voltage
VZAP	Voltage after forward breakdown voltage
VZBN	Zener voltage before reverse breakdown voltage
VZBP	Voltage before forward breakdown voltage
Z	Impedance

APPENDIX A.--SAMPLE PRODUCTION RUN OF SEMCON

This appendix contains examples of plots available through SEMCON and the computer center at the Mobility Equipment Research and Development Center, Fort Belvoir, VA.

09.41.28.

06/09/76

SEMI-CONDUCTOR DAMAGE PROGRAM - VERSION 3F JUNE, 1975

DEVICE: IN3603 JUNCTION: C-A
 MANUFACTURER: FAIRCHILD TECHNICIAN: R. PARSONS DATE: 7-23-73

NO.	PT	T00C	VUC	VP	IP	TD	POWER	ENERGY	IMPEDANCE	VZB*	VZA*	VZB-	VZA-	GAINB	GAINA	PIN	FAIL	REMARKS
1	1	10E-04	100.0	100.0	0.0	10E-04	0.0	0.0	0.0	1.0	1.0	160.0	160.0	0.00	0.00	0.00	0.00	
1	2	10E-04	110.0	105.0	0.0	10E-04	0.0	0.0	0.0	1.0	1.0	160.0	160.0	0.00	0.00	0.00	0.00	NO
1	3	10E-04	120.0	115.0	0.0	10E-04	0.0	0.0	0.0	1.0	1.0	160.0	160.0	0.00	0.00	0.00	0.00	YES
2	1	10E-04	60.0	60.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	92.0	92.0	0.00	0.00	0.00	0.00	NO
2	2	10E-04	70.0	70.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	92.0	92.0	0.00	0.00	0.00	0.00	NO
2	3	10E-04	80.0	80.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	92.0	92.0	0.00	0.00	0.00	0.00	NO
2	4	10E-04	90.0	90.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	92.0	92.0	0.00	0.00	0.00	0.00	NO
2	5	10E-04	100.0	100.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	92.0	92.0	0.00	0.00	0.00	0.00	NO
2	6	10E-04	110.0	110.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	92.0	92.0	0.00	0.00	0.00	0.00	NO
3	1	10E-04	80.0	80.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	90.0	90.0	0.00	0.00	0.00	0.00	NO
3	2	10E-04	90.0	90.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	90.0	90.0	0.00	0.00	0.00	0.00	NO
3	3	10E-04	100.0	100.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	90.0	90.0	0.00	0.00	0.00	0.00	YES
3	4	10E-04	110.0	110.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	90.0	90.0	0.00	0.00	0.00	0.00	YES
4	1	10E-04	80.0	80.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	98.0	98.0	0.00	0.00	0.00	0.00	NO
4	2	10E-04	90.0	90.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	98.0	98.0	0.00	0.00	0.00	0.00	NO
4	3	10E-04	100.0	100.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	98.0	98.0	0.00	0.00	0.00	0.00	NO
4	4	10E-04	110.0	110.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	98.0	98.0	0.00	0.00	0.00	0.00	NO
5	1	10E-04	80.0	80.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	YES
5	2	10E-04	90.0	90.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	NO
5	3	10E-04	100.0	100.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	YES
6	1	10E-04	80.0	80.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	NO
6	2	10E-04	90.0	90.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	NO
6	3	10E-04	100.0	100.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	YES
7	1	10E-04	80.0	80.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	NO
7	2	10E-04	90.0	90.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	NO
7	3	10E-04	100.0	100.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	NO
7	4	10E-04	110.0	110.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	86.0	86.0	0.00	0.00	0.00	0.00	YES
8	1	10E-04	80.0	80.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	88.0	88.0	0.00	0.00	0.00	0.00	NO
8	2	10E-04	90.0	90.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	88.0	88.0	0.00	0.00	0.00	0.00	NO
8	3	10E-04	100.0	100.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	88.0	88.0	0.00	0.00	0.00	0.00	NO
8	4	10E-04	110.0	110.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	88.0	88.0	0.00	0.00	0.00	0.00	NO
8	5	10E-04	118.0	118.0	0.0	10E-04	0.0	0.0	0.0	0.3	0.3	88.0	88.0	0.00	0.00	0.00	0.00	NO
9	1	50E-05	80.0	80.0	0.0	50E-05	0.0	0.0	0.0	0.3	0.3	93.0	93.0	0.00	0.00	0.00	0.00	YES
9	2	50E-05	90.0	90.0	0.0	50E-05	0.0	0.0	0.0	0.3	0.3	93.0	93.0	0.00	0.00	0.00	0.00	NO
9	3	50E-05	100.0	100.0	0.0	50E-05	0.0	0.0	0.0	0.3	0.3	93.0	93.0	0.00	0.00	0.00	0.00	NO
9	4	50E-05	112.0	112.0	0.0	50E-05	0.0	0.0	0.0	0.3	0.3	93.0	93.0	0.00	0.00	0.00	0.00	NO
10	1	50E-05	80.0	80.0	0.0	50E-05	0.0	0.0	0.0	0.3	0.3	93.0	93.0	0.00	0.00	0.00	0.00	YES
10	2	50E-05	90.0	90.0	0.0	50E-05	0.0	0.0	0.0	0.3	0.3	93.0	93.0	0.00	0.00	0.00	0.00	NO
10	3	50E-05	100.0	100.0	0.0	50E-05	0.0	0.0	0.0	0.3	0.3	93.0	93.0	0.00	0.00	0.00	0.00	NO
10	4	50E-05	110.0	110.0	0.0	50E-05	0.0	0.0	0.0	0.3	0.3	93.0	93.0	0.00	0.00	0.00	0.00	YES

APPENDIX A

REVERSE FAILURE CURVES AND DATA FOR DEVICE 1N3600

FITTING PARAMETER FOR $P=A \cdot T^{0.0}(-1)$ IS: $A = 1.40305738E-04$ $OMEGA = 2.14182431E-02$

FITTING PARAMETER FOR $P=B \cdot T^{0.0}(-.5)$ IS: $B = 1.21107459E-01$ $OMEGA = 1.19645330E-02$

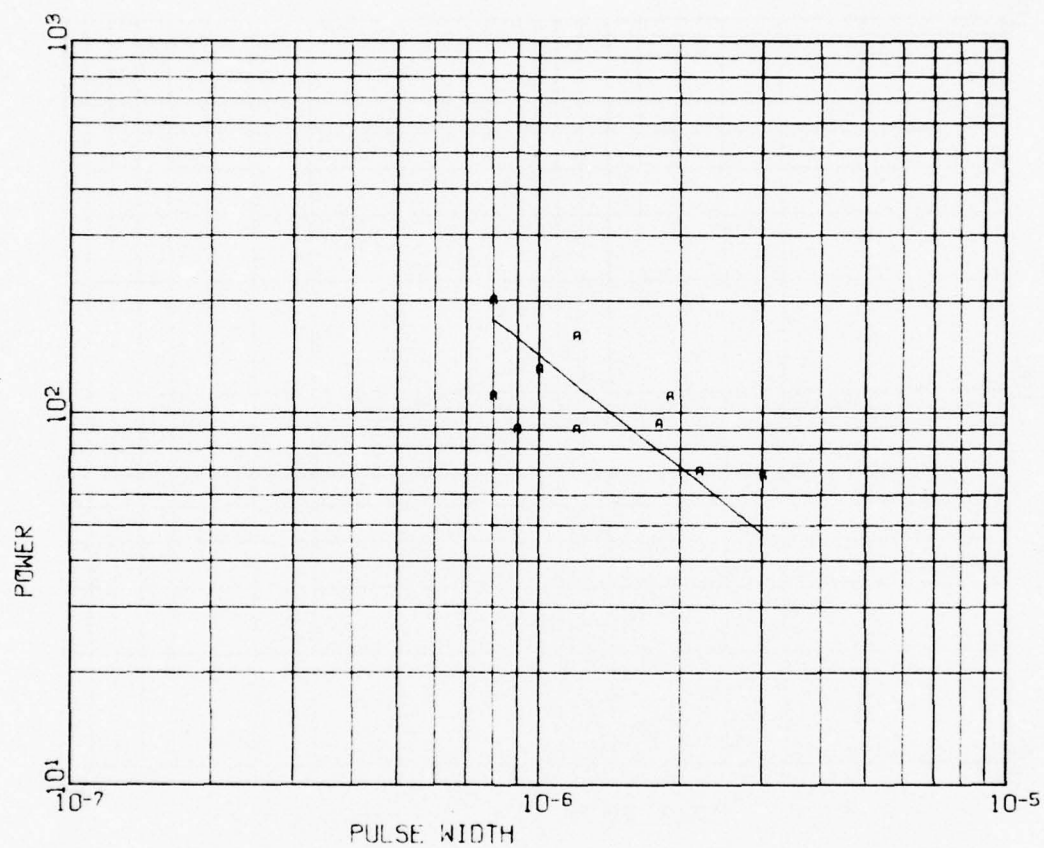
FITTING PARAMETERS FOR $P=A \cdot T^{0.0}(-1) + B \cdot T^{0.0}(-.5)$ ARE: $A = 3.35628819E-05$ $OMEGA = 1.40030432E-02$
 $B = 9.28177482E-02$

A AND B FOUND IN 24 ITERATIONS MINIMUM OF $S(A,B) = 1.12024345E-01$

GAUSS CRITERION OF GOODNESS OF FIT
 THE EQUATION WHICH BEST FITS THIS DATA IS:

$P=B \cdot T^{0.0}(-.5)$

APPENDIX A

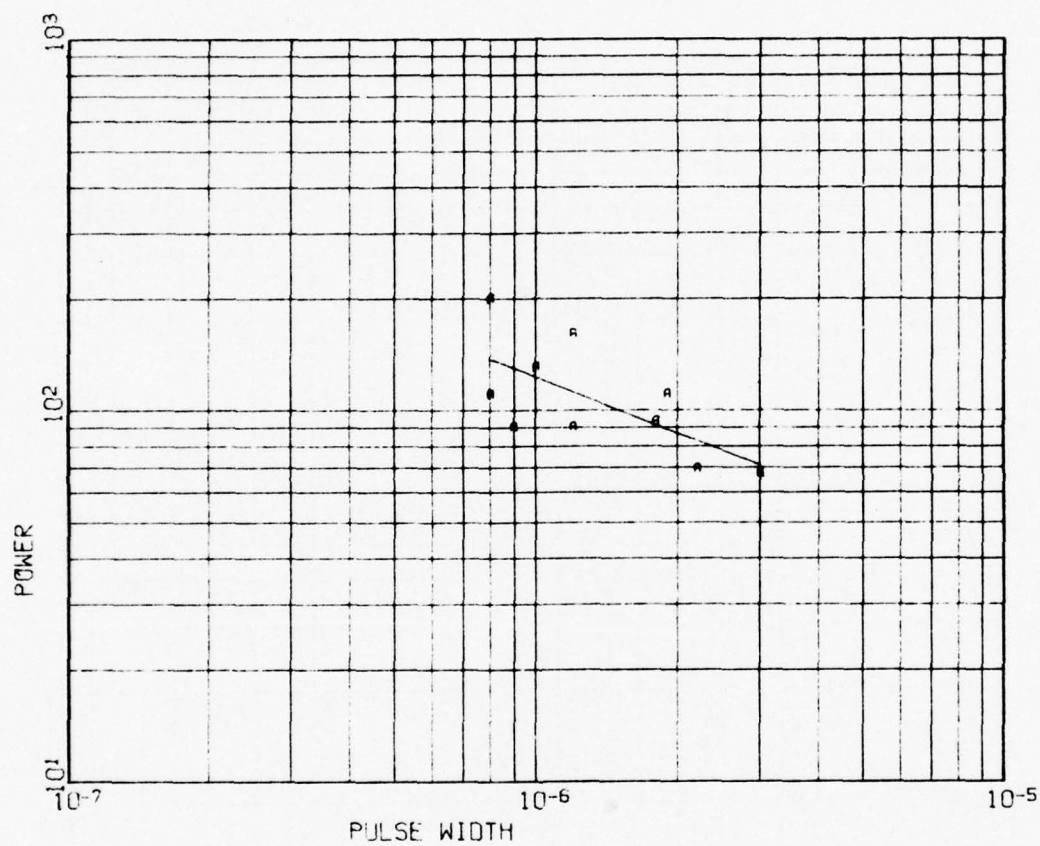


DEVICE: IN3600

REVERSE FAILURE

FIT TO $P=A \cdot T^{**}(-1)$

APPENDIX A

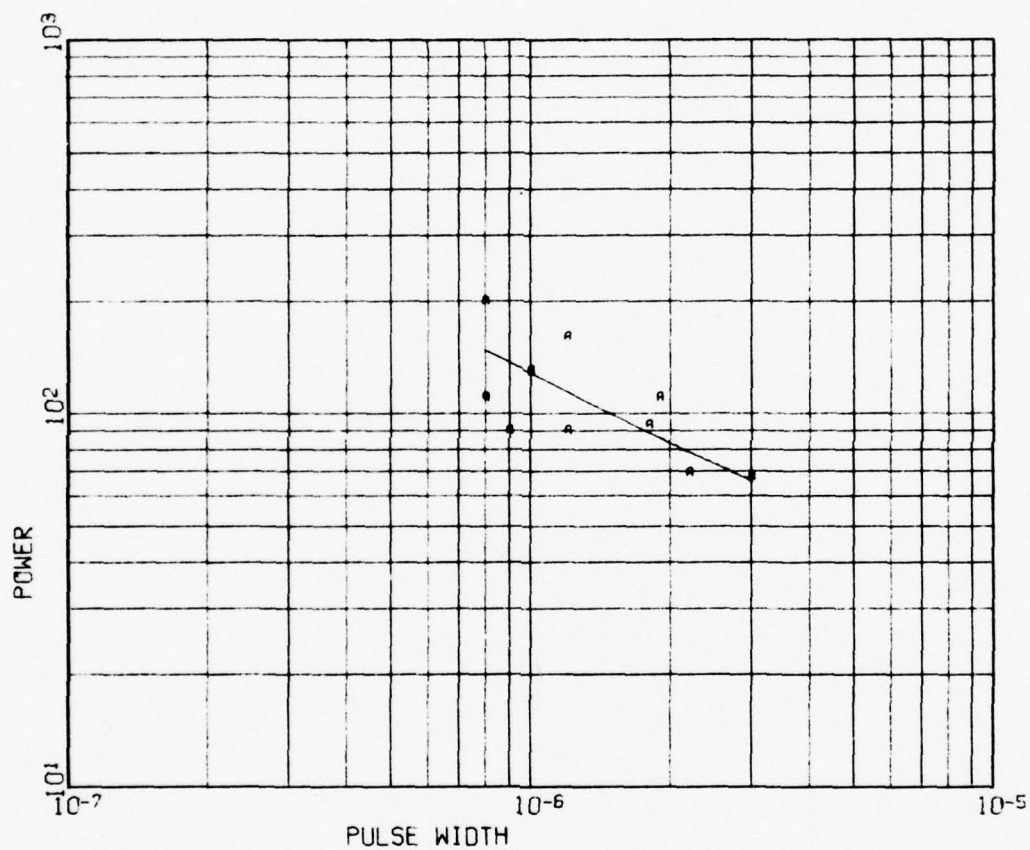


DEVICE: IN3600

REVERSE FAILURE

FIT TO $P = B \cdot T^{-.5}$

APPENDIX A



DEVICE: IN3600 REVERSE FAILURE
 FIT TO $P=A*T^{**}(-1)+B*T^{**}(-.5)$

APPENDIX B.--SAMPLE PRODUCTION RUN OF SEMCON

This appendix contains examples of plots available through SEMCON and the Mohawk Data Sciences computing system.

SEMI-CONDUCTOR DAMAGE PROGRAM - VERSION OF JUNE, 1975

06/10/76 11.58.41.

DEVICE: IN3600 DEVICE TYPE: DIODE JUNCTION: C-A
 MANUFACTURER: FAIRCHILD TECHNICIAN: R. PARSONS DATE: 7-23-73

IDENTIFICATION: REVERSE FAILURE

PULSE WIDTH	POWER	PULSE WIDTH	POWER	PULSE WIDTH	POWER
8.000E-07	1.100E+02	1.200E-06	9.000E+01	1.900E-06	1.100E+02
8.000E-07	2.800E+02	1.200E-06	1.600E+02	2.200E-06	6.900E+01
9.000E-07	9.000E+01	1.800E-06	9.300E+01	3.000E-06	6.700E+01
1.000E-06	1.300E+02				

REVERSE FAILURE CURVES AND DATA FOR DEVICE IN3600

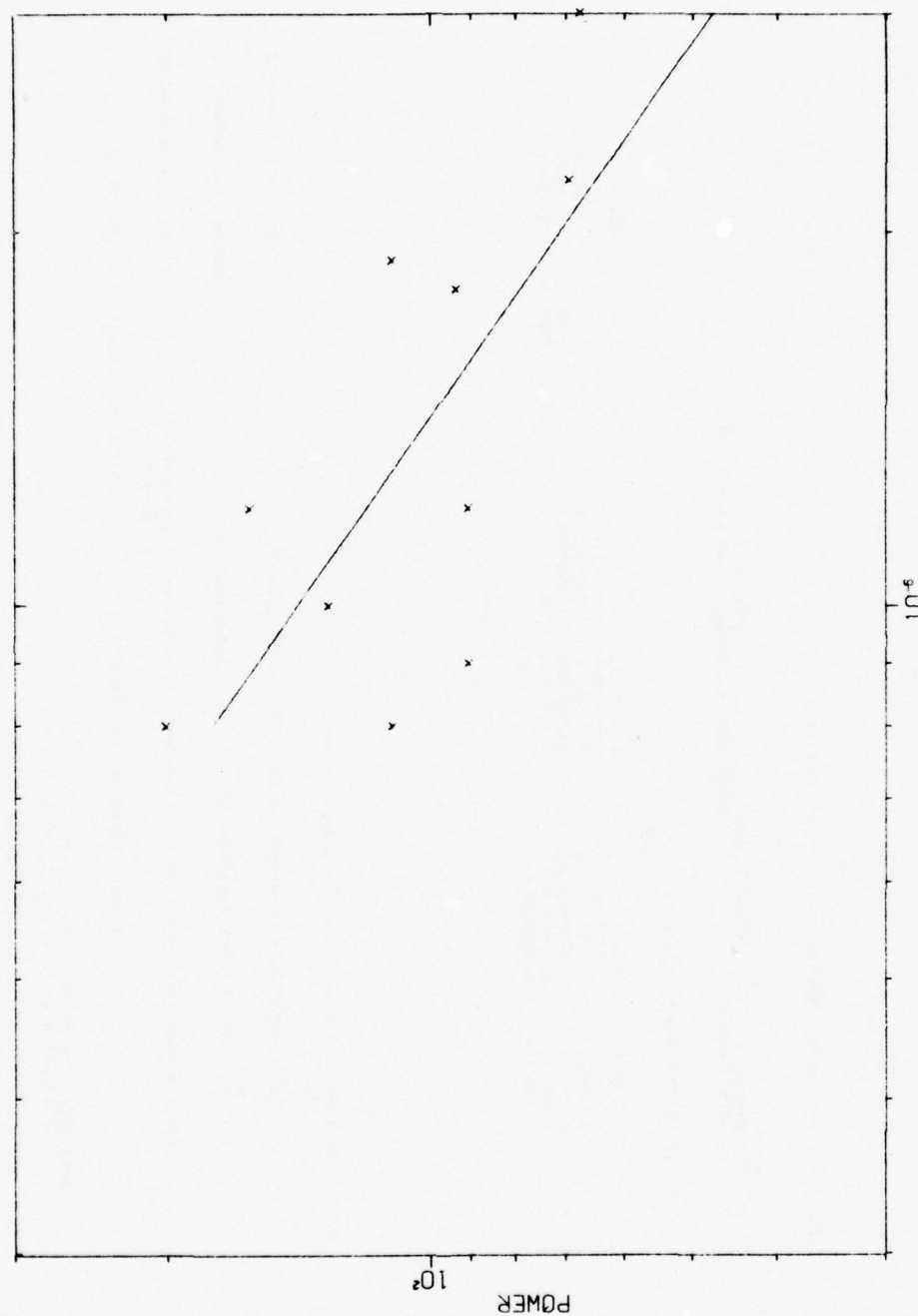
FITTING PARAMETER FOR $P=A \cdot T^{0.5}(-1)$ IS: $A= 1.41779212E-04$ $\Omega\text{EGA}= 2.16628588E-02$ FITTING PARAMETER FOR $P=B \cdot T^{0.5}(-.5)$ IS: $B= 1.22460156E-01$ $\Omega\text{EGA}= 1.21928344E-02$ FITTING PARAMETERS FOR $P=A \cdot T^{0.5}(-1) + B \cdot T^{0.5}(-.5)$ ARE: $A= 3.39153554E-05$
 $B= 9.37925093E-02$ $\Omega\text{EGA}= 1.42629648E-02$ A AND B FOUND IN 24 ITERATIONS MINIMUM OF $S(A,B)= 1.14103719E-01$

GAUSS CRITERION OF GOODNESS OF FIT
 THE EQUATION WHICH BEST FITS THIS DATA IS:
 $P=B \cdot T^{0.5}(-.5)$

APPENDIX B

LEAST SQUARES FIT TO DATA

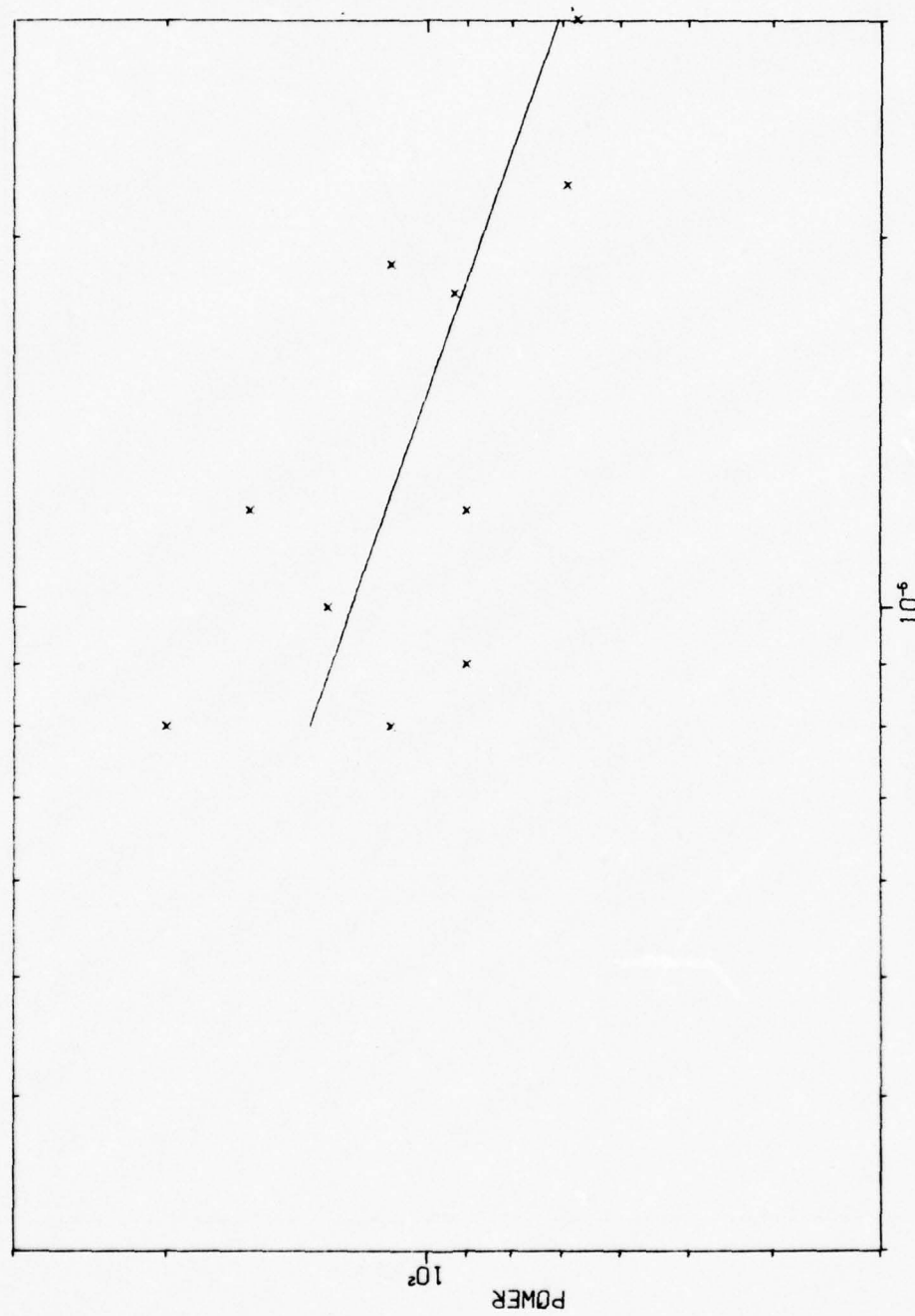
DEVICE: IN3600 REVERSE FAILURE FIT TO $P=A \cdot T^{0.5} (-1)$



07/21/75 14:49:54

LEAST SQUARES FIT TO DATA

DEVICE: INS600 REVERSE FAILURE FIT TO $P = B \cdot T^{.5}$ (-.5)



07/21/75 14.49.56

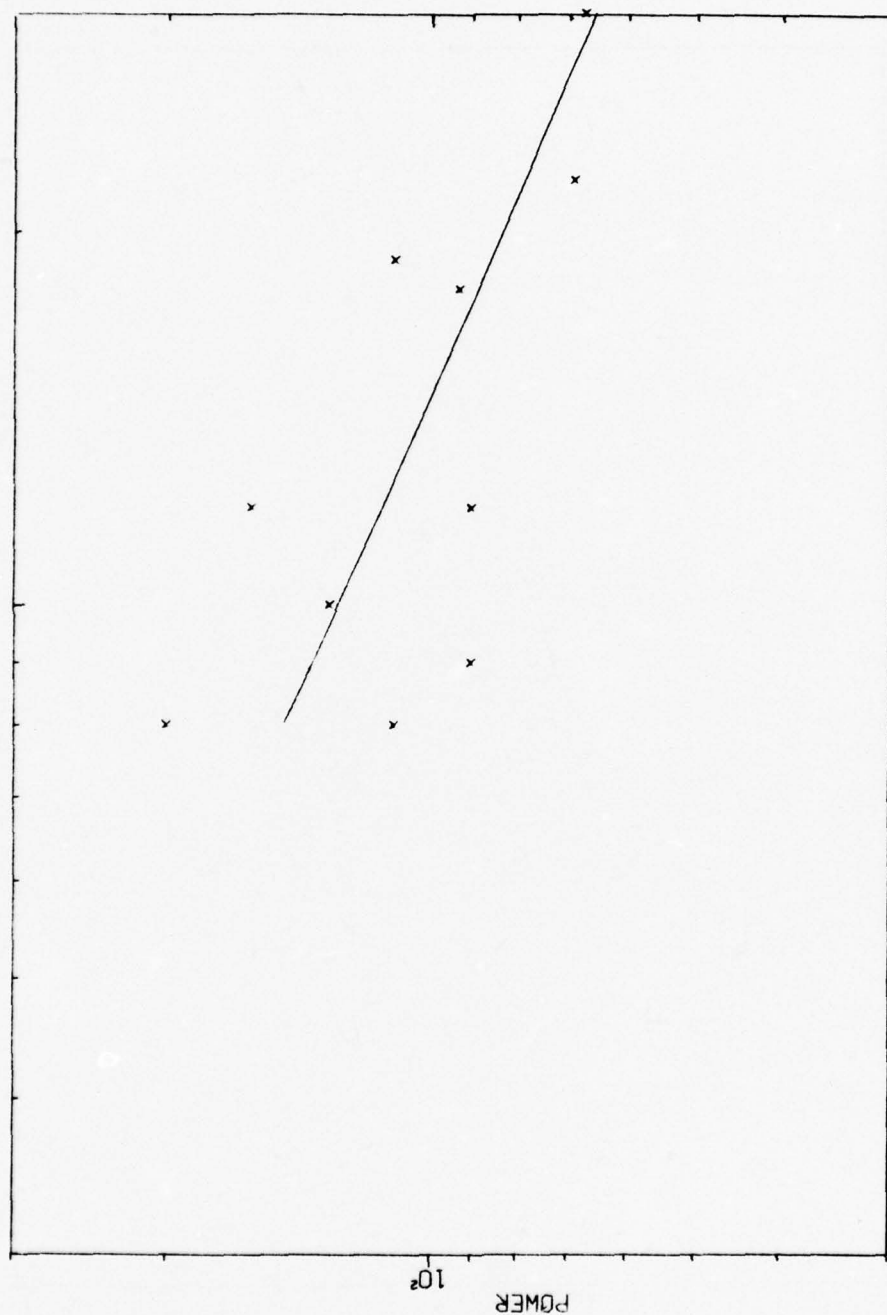
APPENDIX B

LEAST SQUARES FIT TO DATA

DEVICE: IN3000

REVERSE FAILURE

FIT TO $P=A \cdot T^{0.5} (-1) + B \cdot T^{0.5} (-1.5)$



07/21/75 14.49.59.

APPENDIX C.--LISTING OF SEMCON

This appendix contains a complete listing of SEMCON.

PROGRAM SEMCON 74/74 OPT=1 FTN 4.5414 06/01/76 14.04.49 PAGE 1

```

1  PROGRAM SEMCON(INPUT,OUTPUT,TAPES=INPUT,TAPE6=OUTPUT,TAPE1,TAPE7)
2  SEMCON
3  SEMCON
4  SEMCON
5  SEMCON
6  SEMCON
7  SEMCON
8  SEMCON
9  SEMCON
10 SEMCON
11 SEMCON
12 SEMCON
13 SEMCON
14 SEMCON
15 SEMCON
16 SEMCON
17 SEMCON
18 SEMCON
19 SEMCON
20 SEMCON
21 SEMCON
22 SEMCON
23 SEMCON
24 SEMCON
25 SEMCON
26 SEMCON
27 SEMCON
28 SEMCON
29 SEMCON
30 SEMCON
31 SEMCON
32 SEMCON
33 SEMCON
34 SEMCON
35 SEMCON
36 SEMCON
37 SEMCON
38 SEMCON
39 SEMCON
40 SEMCON
41 SEMCON
42 SEMCON
43 SEMCON
44 SEMCON
45 SEMCON
46 SEMCON
47 SEMCON
48 SEMCON
49 SEMCON
50 SEMCON
51 SEMCON
52 SEMCON
53 SEMCON
54 SEMCON
55 SEMCON
56 SEMCON
57 SEMCON
58 SEMCON

      INTEGER FLAG,FAIL,PULSE
      REAL IP,JUNC,MAN1,MAN2
      REAL IPREF,IPEFF
      SEMI-CONDUCTOR DATA REDUCTION PROGRAM

      COMMON /P1/ P(600),TD(600),E(600),TDOC(600),Z(600),VDC(600),
1      IP(600),FAIL(600)
      COMMON /P2/ FLAG,IPREF,IPREF,DEV
      COMMON /P3/ IPREF(600),IPREF(600),IPREF(600),IPREF(600),
1      VDCRF(600),IPREF(600),P1(600),P2(600),P3(600)
      COMMON /P4/ P(600),TDOC(600),E(600),TDOC(600),Z(600),
1      VDCRF(600),IPREF(600)
      COMMON /P5/ P(600),IPREF(600)
      COMMON /P6/ GAUSS(3),S
      COMMON /P7/ IPLOT,ISEM,ITYPE
      COMMON /P8/ DEVTYPE1,DEVTYPE2,JUNC,MAN1,MAN2,TECH,DATEE,ISTOP
      DIMENSION NPULS(300),VP(600),VZBP(600),VZAP(600),VZBN(600),
1      ZAN(600),REMAR1(600),REMAR2(600),GAINB(600),
2      GAINA(600),NDEV(600),PULSE(600)

      PRINT IO
10  FORMAT(I11)
      CALL DATEIOAT)
      CALL TIMEIOIN)
      PRINT 20,DATE,TIM
20  FORMAT(/,/,IX,44H SEMI-CONDUCTOR DAMAGE PROGRAM - VERSION OF ,
      /,2XJUNE,1975 ,3X,A10,5X,A10,/,/,/)
25  READ(5,25) IND,FLAG,IPREF,IPREF,IPREF,IPREF,IPREF,IPREF,ITYPE
      FORMAT(49X,I11,8X,I2,2(9X,I11))
30  READ(5,30) NUMB,DEV,DEVTYPE1,DEVTYPE2,JUNC,MAN1,MAN2,TECH,DATEE
      FORMAT(13,A8,2A10,A9,4A10)
35  IF(ISTOP.NE.1) WRITE(6,33)
      FORMAT(17HPM THIS JOB PLOTS)
      IF(ISEM.EQ.0) GO TO 35
      CALL DWDNAT(NUMB)
      GO TO 210
35  L=0
      DO 70 I=1,NUMB
      READ(5,40) NPULS(I)
40  FORMAT(I2)
      NPUL=NPULS(I)
      DO 70 J=1,NPUL
      L=L+1
      READ(5,50) NDEV(L),PULSE(L),TDOC(L),VDC(L),VP(L),IP(L),
      ITOL(),VZBP(L)
50  FORMAT(13,I2,E10.3,F10.3,F10.3,F10.3,E10.3,F10.3)
      READ(5,60) VZAP(L),VZBN(L),VZAN(L),GAINB(L),GAINA(L),PIN(L),
      REMAR1(L),REMAR2(L)
60  FORMAT(3F10.3,2(2PE10.2),A2,A10,A9)
70  CONTINUE
      NUM=L
      DO 90 K=1,NUM
      PINI=0.
      EIK=0.

```

APPENDIX C

PROGRAM SEMCON	74/74	OPT=1	FTN 4,5+14	06/01/76	14-04-49	PAGE	2
60			Z(K)=0. IF(IP(K)-LE-0) GO TO 80 IF(VP(K)-LE-0) GO TO 80 P(K)=VP(K)*IP(K) E(K)=P(K)*TO(K) Z(K)=VP(K)*VZBPK(I)/IP(K) IF(Z(K)-LT-0.) Z(K)=0. 80 CALL FAILUR(VZBPK(I),VZAP(K),FAIL(K)) IF(FAIL(K)-EQ-3HYES) GO TO 90 CALL FAILUR(VZBN(K),VZAN(K),FAIL(K)) IF(FAIL(K)-EQ-3HYES) GO TO 90 CALL FAILUR(GAINB(K),GAINA(K),FAIL(K)) 90 CONTINUE IF(ISTOP-EQ-3) GO TO 145 PRINT 100,DEV,DEVTYP1,DEVTYP2,JUNC,MAN1,MAN2,TECH,DATEE 100 FORMAT(5X,8HDEVICE: ,A8,3X,13HDEVICE TYPE: ,2A10,3X, 110HJUNCTION: ,A9,7,5X,14HMANUFACTURER: ,2A10,3X,12HTECHNICIAN: , 2A10,3X,6HDATE: ,A10,7,7) PRINT 110 110 FORMAT(1X,3HNO.,1X,2HPT,3X,4HTOCC,6X,3HVOC,4X,2HVP,4X,2HIP,5X, 12HTD,6X,5HPWER,3X,6HENERGY,1X,9HIMPEDANCE,2X,4HVZB,2X,4HVZA, 22X,4HVZB,2X,4HVZA,2X,5HGAINB,1X,5HGAINA,1X,3HPIN,1X,4HFAIL,5X, 37HREMARKS) PRINT 120 120 FORMAT(1X,3H---,1X,2H---,3X,4H---,6X,3H---,4X,2H---,5X, 12H---,6X,5H---,3X,6H---,1X,9H---,2X,4H---,2X,4H---, 22X,4H---,2X,4H---,2X,5H---,1X,5H---,1X,3H---,1X,4H---,5X, 37H-----) L=0 DO 140 I=1,NUMB NPUL=NPULS(I) DO 140 J=1,NPUL L=L+1 PRINT 130,NDDEV(L),PULSE(L),TOCC(L),VOC(L),VP(L),IP(L),TO(L),P(L), 2PIN(L),FAIL(L),REMARK(L),REMARK2(L) 130 FORMAT(1H ,13,1H-,12,1X,E8.2,1X,F6.1,1X,F6.1,1X,F5.1,1X,E8.2, 11X,E8.2,1X,E8.2,1X,E8.2,1X,F5.1,1X,F5.1,1X,F5.1,1X,F5.1,1X, 2F6.2,1X,F5.1,1X,A2,1X,A3,1X,A10,A9) 140 CONTINUE IF(ISTOP-EQ-1) GO TO 210 145 CONTINUE PRINT 150 150 FORMAT(1H1) CALL FRFAIL(NUM,KNUM,JNUM) IF(IPRAN-EQ-4) GO TO 160 IF(IPRAN-EQ-0) GO TO 200 160 GO TO (170,180,170),IND 170 CALL DIRECT(KNUM,1,A,B,AE,BE,IT) CALL WRITE(A,B,AE,BE,1,IT) CALL GAUSS CALL PLOTT(KNUM,JNUM,1) IF(IND-EQ-1) GO TO 190 180 IF(JNUM-EQ-0) GO TO 190 CALL DIRECT(JNUM,2,A,B,AE,BE,IT) CALL WRITE(A,B,AE,BE,2,IT) CALL GAUSS	59 SEMCON 60 SEMCON 61 SEMCON 62 SEMCON 63 SEMCON 64 SEMCON 65 SEMCON 66 SEMCON 67 SEMCON 68 SEMCON 69 SEMCON 70 SEMCON 71 SEMCON 72 SEMCON 73 SEMCON 74 SEMCON 75 SEMCON 76 SEMCON 77 SEMCON 78 SEMCON 79 SEMCON 80 SEMCON 81 SEMCON 82 SEMCON 83 SEMCON 84 SEMCON 85 SEMCON 86 SEMCON 87 SEMCON 88 SEMCON 89 SEMCON 90 SEMCON 91 SEMCON 92 SEMCON 93 SEMCON 94 SEMCON 95 SEMCON 96 SEMCON 97 SEMCON 98 SEMCON 99 SEMCON 100 SEMCON 101 SEMCON 102 SEMCON 103 SEMCON 104 SEMCON 105 SEMCON 106 SEMCON 107 SEMCON 108 SEMCON 109 SEMCON 110 SEMCON 111 SEMCON 112 SEMCON 113 SEMCON 114 SEMCON 115 SEMCON			

```

1115 CALL PLOTT(KNUM,JNUM,2)
      CONTINUE
190 IF(IPRAM,EQ,0) GO TO 210
      200 CALL PLOTT(KNUM,JNUM,3)
      210 STOP
      END
1120

```

CARD NR.	SEVERITY	DETAILS	DIAGNOSIS OF PROBLEM
105	1		AN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS	DEF LINE	REFERENCES	RELOCATION		SN TYPE		VARIABLES	SENCON	1
10215									
11153	A	REAL							
11155	AE	REAL							
11154	B	REAL							
11156	BE	REAL							
11140	DAT	REAL							
6	DATEE	REAL							
3	DEV	REAL							
0	DEVTP1	REAL							
1	DEVTP2	REAL							
3410	E	REAL							
2240	EFF	REAL							
2260	ERF	REAL							
111300	FAIL	INTEGER							
1	FLAG	INTEGER							
42424	GAINA	REAL							
423134	GAINB	REAL							
0	GAUS	REAL							
111144	I	INTEGER							
0	IND	INTEGER							
10150	IP	REAL							
7020	IPFF	REAL							
0	IPLDT	INTEGER							
2	IPRAM	INTEGER							
7020	IPRF	REAL							
1	ISEM	INTEGER							
7	ISTOP	INTEGER							
111157	IT	INTEGER							
2	ITYPE	INTEGER							
22246	J	INTEGER							
111152	JNUM	INTEGER							
2	JUNC	REAL							
106		REFS	106	107	112	113			
106		REFS	106	107	112	113			
106		REFS	106	107	112	113			
26		REFS	26	28					
20		REFS	20	72	DEFINED	33			
12		REFS	12	72	DEFINED	33			
20		REFS	20	72	DEFINED	33			
20		REFS	20	72	DEFINED	33			
10		REFS	10	91	DEFINED	57			62
15		REFS	15						
13		REFS	13						
7		REFS	7	10	65	66			67
91		REFS	91						68
7		REFS	7	12	DEFINED	31			
21		REFS	21	69	91	DEFINED	50		
21		REFS	21	69	91	DEFINED	50		
18		REFS	18						
42		REFS	42	44	88	DEFINED	41		87
12		REFS	12	105	110	DEFINED	31		
8		REFS	8	10	59	61	63		91
DEFINED		REFS	DEFINED						
9		REFS	9	15					
19		REFS	19	DEFINED	31	117	DEFINED		31
12		REFS	12	103	104				
9		REFS	9	13					
19		REFS	19	37	DEFINED	31	98		31
20		REFS	20	35	71				
106		REFS	106	107	112	113			
19		REFS	19	DEFINED	31				
45		REFS	45	89					
DEFINED		REFS	DEFINED						
102		REFS	102	109	111	112	115		118
8		REFS	8	20	72	DEFINED	33		

APPENDIX C

PROGRAM SEMCON			74/74	OPT=1	RELOCATION		FTN 4.5+4.24										06/01/76	14.04.49	PAGE	4	
VARIABLES	SN	TYPE						REFS	56	57	58	59	60	3061	3062						
11150 K		INTEGER					DEFINED	2064	55	3065	66	3067	68	3069							
11151 KNUM		INTEGER					REFS	102	46	106	109	115	118			20091					
11143 L		INTEGER					DEFINED	40	86	8047	8050	54	90								
3 MAM1		REAL				G	REFS	8	20	72	DEFINED	33									
4 MAM2		REAL				G	REFS	8	20	72	DEFINED	33									
25414 NDEV		INTEGER					REFS	21	91	DEFINED	47										
11145 NPUL		INTEGER					REFS	45	89	DEFINED	44	88									
12310 NPULS		INTEGER					REFS	21	91	DEFINED	42										
11147 NUM		INTEGER					REFS	55	102	DEFINED	54										
11142 NUMB		INTEGER					REFS	38	41	87	DEFINED	33									
11130 P		REAL			/		REFS	10	62	91	DEFINED	56				61					
0 PFF		REAL			/		REFS	15	91	DEFINED	50										
0 PJM		REAL			/		REFS	10													
11130 PP		REAL			/		REFS	17													
0 PRF		REAL			B		REFS	13													
11160 PULSE		INTEGER					REFS	7	21	91	DEFINED	47									
10150 P1		REAL			B		REFS	13													
111300 P2		REAL			B		REFS	13													
12430 P3		REAL			B		REFS	13													
20654 REMAR1		REAL					REFS	21	91	DEFINED	50										
22004 REMAR2		REAL					REFS	21	91	DEFINED	50										
3 S		REAL			E		REFS	18													
0 T		REAL			D		REFS	17													
2260 TD		REAL			/		REFS	20	62	91	DEFINED	47									
1130 TDF		REAL			/		REFS	15													
4540 TDF		REAL			/		REFS	10	91	DEFINED	47										
3410 TDF		REAL			/		REFS	15													
3410 TDF		REAL			/		REFS	15													
3410 TDF		REAL			B		REFS	13													
1130 TDF		REAL			B		REFS	13													
5 TECH		REAL			G		REFS	20	72	DEFINED	33										
11141 TIM		REAL					REFS	27	28												
7020 VDC		REAL			/		REFS	10	91	DEFINED	47										
5670 VDC		REAL			/		REFS	15													
5670 VDC		REAL			C		REFS	13													
5670 VDC		REAL			B		REFS	13													
12764 VP		REAL					REFS	21	60	61	63	91									
							DEFINED	47													
17524 VZAM		REAL					REFS	21	67	91	DEFINED	50									
15244 VZAP		REAL					REFS	21	65	91	DEFINED	50									
16374 VZBN		REAL					REFS	21	67	91	DEFINED	50									
14114 VZBP		REAL					REFS	21	63	65	91	DEFINED	47								
5670 Z		REAL			/		REFS	10	64	91	DEFINED	58				63					
4540 ZFF		REAL			/		REFS	15													
4540 ZRF		REAL			B		REFS	13													
FILE NAMES			MODE																		
0 INPUT		FMT				WRITES		24	28	72	76	81	91	100							
2041 OUTPUT		FMT				WRITES		31	33	42	47	50									
4102 TAPE1		FMT				WRITES		35													
2041 TAPE6		FMT				WRITES															
6143 TAPE7		FMT				WRITES															

PROGRAM			SECCUN	74/74	DPT=1
EXTERNALS			TYPE	ARGS	REFERENCES
DATE				1	26
DIRECT				7	106
FAILUR				3	65
FREAIL				3	102
GAUSS				0	108
ONNDAT				1	38
PLOTT				3	109
TIME				1	27
WRITE				6	107

STATEMENT LABELS			DEF LINE	REFERENCE
10821	10	FMT	25	24
10830	20	FMT	29	28
10855	25	FMT	31	32
10676	30	FMT	34	33
10704	33	FMT	36	35
10242	35	FMT	40	37
10715	40	FMT	43	42
10733	50	FMT	49	47
10755	60	FMT	52	50
0	70	FMT	53	41
10336	80	FMT	65	59
10361	90	FMT	70	55
10774	100	FMT	72	73
11014	110	FMT	77	76
11040	120	FMT	82	81
11110	130	FMT	94	91
0	140	FMT	97	87
10452	145	FMT	99	71
11131	150	FMT	101	100
10461	160	FMT	105	103
10471	170	FMT	106	2*105
10502	180	FMT	111	105
10512	190	FMT	116	110
10513	200	FMT	118	104
10515	210	FMT	119	39

MEMBERS	-	BIAS NAME(LE
1800 F	0 PIN	(600
3600 VDC	0 IND	(11
3 DEF	0 PRF	(11
1800 TODCRF	1800 TODCRF	(600
3600 IPRF	3600 IPRF	(600
5400 P3	5400 P3	(600
0 PFF	0 PFF	(600
1800 TODCFF	1800 TODCFF	(600
3600 IPFF	3600 IPFF	(600

APPENDIX C

PROGRAM SENCUN		74/74	DPT=1	FTN 4.5+414	06/01/76	14.04.49	PAGE	6
COMMON BLOCKS	LENGTH	MEMBERS - BIAS NAME(LENGTH)						
D	1200	0 T (600)		600 PP (600)				
E	4	0 GAUS (3)		3 S (1)				
F	3	0 IPLOT (1)		1 ISEM (1)				
G	8	0 DEVP1(1)		1 DENTYP2(1)				
		3 MAN1 (1)		4 MAN2 (1)				
		6 DATEE (1)		7 1STCP (1)				
STATISTICS								
PROGRAM LENGTH		163378	7391					
BUFFER LENGTH		102058	4229					
CM LABELED COMMON LENGTH		262338	11419					
CM BLANK COMMON LENGTH		124306	5400					
				2 ITYPE (1)				
				2 JUNC (1)				
				5 TECH (1)				

SUBROUTINE FRFAIL 74/74 OPT=1

```

1  SUBROUTINE FFAIL(NUM,KNUM,JNUM)
   REAL IPRF,IPFF
   REAL IP
   COMMON PINT6001,P(600),TD(600),E(600),TDUC(600),Z(600),VOC(600),
5    IP(600),FAIL(600)
   COMMON/B/PRF(600),TORE(600),ERF(600),TDCRFF(600),ZRF(600),
   VOCRF(600),IPRF(600),P(1600),P2(600),P3(600)
10  COMMON/C/PPF(600),TDFF(600),EFF(600),TDCRFF(600),ZFF(600),
   K=1
   VOCFF(600),IPFF(600)
   J=1
   DD 30 I=1,NUM
   IF (FAIL(I)-EQ.3H NO) GO TO 30
   IF (PINT(I)-EQ.2HC+) GO TO 10
   IF (PINT(I)-EQ.2HA+) GO TO 20
   GO TO 30
10  TCRF(K)=TD(I)
   PRF(K)=P(I)
   ERF(K)=E(I)
   ZRF(K)=Z(I)
   VOCRF(K)=VOC(I)
   IPRF(K)=IP(I)
   TDCRFF(K)=TDC(I)
   K=K+1
   GO TO 30
20  TDFF(J)=TD(I)
   PPF(J)=P(I)
   EFF(J)=E(I)
   ZFF(J)=Z(I)
   VOCFF(J)=VOC(I)
   IPFF(J)=IP(I)
   TDCRFF(J)=TDC(I)
   J=J+1
   GO TO 30
30  CONTINUE
   KNUM=K-1
   JNUM=J-1
   RETURN
   END

```

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS	DEF LINE	REFERENCES
3 FRFAIL	1	38

VARIABLES	SV	TYPE	RELOCATION
3410 F	REAL	ARRAY	/ /
2260 EFF	REAL	ARRAY	C
2260 EFF	REAL	ARRAY	B
1300 FAIL	REAL	ARRAY	/ /
65 I	INTEGER		

REFS	4	19	28
REFS	8	DEFINED	28
REFS	6	DEFINED	19
REFS	4	13	
REFS	13	14	15
21	22	23	26
31	32	DEFINED	12

17	18	19	20
27	28	29	30

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74/74 OPT=1

SUBROUTINE FRAIL

VARIABLES	SN	TYPE	RELOCATION	REFS	3	4	22	31	31	32
10150 IP		REAL	ARRAY / /	REFS	2	8	DEFINED	31		
7020 IPFF		REAL	ARRAY C	REFS	2	6	DEFINED	22		
7020 IPRF		REAL	ARRAY B	REFS	26	27	28	29	30	31
64 J		INTEGER		REFS	37	DEFINED	11	33		
0 JNMJ		INTEGER	F.P.	DEFINED	1	37	19	20	21	22
53 K		INTEGER		REFS	17	18	10	24		23
0 KNUM		INTEGER	F.P.	DEFINED	36	36				
0 NUM		INTEGER	F.P.	REFS	12	DEFINED	1			
1130 PFF		REAL	ARRAY / /	REFS	4	18	27			
0 PIN		REAL	ARRAY C	REFS	4	18	27			
0 PRF		REAL	ARRAY / /	REFS	4	14	15			
10150 P1		REAL	ARRAY B	REFS	4	DEFINED	18			
11300 P2		REAL	ARRAY B	REFS	6					
12430 P3		REAL	ARRAY B	REFS	6					
2260 T0		REAL	ARRAY / /	REFS	6					
1130 T0FF		REAL	ARRAY / /	REFS	4	17	26			
4540 T0DC		REAL	ARRAY C	REFS	8	DEFINED	26			
3410 T0DCFF		REAL	ARRAY / /	REFS	8	23	32			
3410 T0DCRF		REAL	ARRAY C	REFS	8	DEFINED	32			
1130 T0RF		REAL	ARRAY B	REFS	6	DEFINED	23			
7020 V0C		REAL	ARRAY / /	REFS	4	DEFINED	17			
5670 V0CFF		REAL	ARRAY C	REFS	4	21	30			
5670 V0CRF		REAL	ARRAY B	REFS	4	DEFINED	30			
5670 Z		REAL	ARRAY / /	REFS	6	DEFINED	21			
4540 ZFF		REAL	ARRAY C	REFS	4	20	29			
4540 ZRF		REAL	ARRAY B	REFS	8	DEFINED	29			
				REFS	6	DEFINED	20			

DEF LINE REFERENCES

17 14

26 15

35 12

13

16

25

34

OPT

PROPERTIES

MEMBERS - BIAS NAME(LENGTH)

0 PIN (600)

1800 E (600)

3600 V0C (600)

0 PRF (600)

1800 T0DCRF (600)

3600 IPRF (600)

5400 P3 (600)

0 PFF (600)

1800 T0DCFF (600)

3600 IPFF (600)

600 P (600)

2400 T0DC (600)

4200 IP (600)

600 T0RF (600)

2400 ZRF (600)

4200 P1 (600)

600 T0FF (600)

2400 ZFF (600)

1200 T0 (600)

3000 Z (600)

4800 FAIL (600)

1200 ERF (600)

3000 V0CRF (600)

4800 P2 (600)

1200 EFF (600)

3000 V0CFF (600)

STATISTICS

PROGRAM LENGTH 666 54

CM LABELED COMMON LENGTH 23730E 10200

CM BLANK COMMON LENGTH 12430E 5400

APPENDIX C

PAGE 1

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FTN 4.5+414

OPT=1

74/74

SUBROUTINE DIRECT

```

1  SUBROUTINE DIRECT(M,A,B,AE,BE,IT)
   INTEGER FLAG
   REAL TPRF,TPFF
   COMMON/A/IND,FLAG,IPRAN,DEV
   COMMON/B/PRF(600),TORF(600),ERF(600),TDCRF(600),ZRF(600),
1  VOCRF(600),IPRF(600),PI(600),P2(600),P3(600)
   COMMON/C/PFF(600),TDFF(600),EFF(600),TDCFF(600),ZFF(600),
1  VOCFF(600),IPFF(600)
   COMMON/D/TI(600),PP(600)
   J=1
   K=1
   GO TO (10,30,55),M
10  DO 20 I=1,N
   IF(PRF(I).EQ.0.) GO TO 15
   T(I)=TORF(I)
   PP(I)=PRF(I)
   J=J+1
15  IF(TI.EQ.N.AND.PRF(I).EQ.0.) J=J+1
20  CONTINUE
   N=J-1
   GO TO 50
30  DO 40 I=1,N
   IF(PFF(I).EQ.0.) GO TO 35
   T(K)=TDFF(I)
   PP(K)=PFF(I)
   K=K+1
35  IF(TI.EQ.N.AND.PFF(I).EQ.0.) K=K+1
40  CONTINUE
   N=K-1
50  CALL SORT(N)
55  GO TO (60,70,60),FLAG
60  CALL ALSQAR(N,A)
   CALL GOODFIT(PP,P2,N,1,1)
   CALL BLSQAR(N,B)
   CALL GOODFIT(PP,P3,N,1,2)
   IF(FLAG.EQ.1) GO TO 80
   IF(FLAG.EQ.3) GO TO 75
70  CALL ALSQAR(N,A)
   CALL BLSQAR(N,B)
75  CALL ABLSQAR(N,A,B,AE,BE,IT)
   CALL GOODFIT(PP,P1,N,2,3)
80  CONTINUE
   RETURN
   END
DIRECT 2
DIRECT 3
DIRECT 4
DIRECT 5
DIRECT 6
DIRECT 7
DIRECT 8
DIRECT 9
DIRECT 10
DIRECT 11
DIRECT 12
DIRECT 13
DIRECT 14
DIRECT 15
DIRECT 16
DIRECT 17
DIRECT 18
DIRECT 19
DIRECT 20
DIRECT 21
DIRECT 22
DIRECT 23
DIRECT 24
DIRECT 25
DIRECT 26
DIRECT 27
DIRECT 28
DIRECT 29
DIRECT 30
DIRECT 31
DIRECT 32
DIRECT 33
DIRECT 34
DIRECT 35
DIRECT 36
DIRECT 37
DIRECT 38
DIRECT 39
DIRECT 40
DIRECT 41
DIRECT 42
DIRECT 43
DIRECT 44
DIRECT 45

```

CARD NR. SEVERITY DETAILS DIAGNOSIS OF PROBLEM
12 1 AN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.
31 1 AN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.

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SUBROUTINE DIRECT 74/74 OPT=1

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS DEF LINE REFERENCES
3 DIRECT 1 43

VARIABLES SN TYPE RELOCATION

0 A REAL F.P.
0 AE REAL F.P.
0 B REAL F.P.
0 BE REAL F.P.
3 DEV REAL A
2260 EFF REAL C
2260 ERF REAL B
214 I INTEGER A
0 IND INTEGER A
7020 IPFF REAL C
2 IPRAM INTEGER A
7020 IPRF REAL B
C IT F.P.
212 J INTEGER F.P.
213 K INTEGER F.P.
0 M F.P.
0 N F.P.

32 REFS
40 REFS
34 REFS
37 REFS
40 REFS
4 REFS
7 REFS
5 REFS
2 REFS
14 REFS
2*27 REFS
4 REFS
3 REFS
4 REFS
4 REFS
3 REFS
40 REFS
15 REFS
16 REFS
17 REFS
18 REFS
26 REFS
11 REFS
12 REFS
13 REFS
34 REFS
1 REFS
7 REFS
9 REFS
5 REFS
5 REFS
5 REFS
5 REFS
5 REFS
9 REFS
7 REFS
7 REFS
5 REFS
5 REFS
7 REFS
5 REFS
7 REFS
7 REFS
5 REFS

38 DEFINED
37 DEFINED
40 DEFINED
1
31
16
22
36
2*18
37
23
24
25
1
17
18
20
27
29
1
22
30
41
27
40
41
18
16
15
24
15
15
41

EXTERNALS TYPE ARCS REFERENCES
ABLSOAR 6 40
ALSQAR 2 32
BLSQAR 2 34
GOODFIT 5 33
SORT 1 30

STATEMENT LABELS
17 10
30 15
0 20
41 30

APPENDIX C

PAGE 3

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FTN 4.5+414

SUBROUTINE DIRECT		74/74	OPT=1	
STATEMENT LABELS		DEF LINE	REFERENCES	
52 35	27	23		
0 40	28	22		
63 50	30	21		
66 55	31	12		
76 60	32	2931		
116 70	37	31		
130 75	40	37		
145 80	42	36		
LOOPS LABEL		FROM-TU	LENGTH	PROPERTIES
24 20	1	13 19	11B	DPI
46 40	1	22 28	11B	DPI
COMMON BLOCKS		MEMBERS - BIAS NAME(LENGTH)		
A	4	0 IND (1)		
B	6000	3 DEV (1)		
		0 PRF (600)		
		1800 TDCCRF (600)		
		3600 IPRF (600)		
		5400 P3 (600)		
C	4200	0 PRF (600)		
		1800 TDCCFF (600)		
		3600 IPFF (600)		
D	1200	0 T (600)		
STATISTICS				
PROGRAM LENGTH		2158	141	
CM LABELED COMMON LENGTH		262148	11404	

1 FLAG (1)
600 TDRF (600)
2400 ZRF (600)
4200 P1 (600)
600 TDFF (600)
2400 ZFF (600)
600 PP (600)

2 IPRAW (1)
1200 ERF (600)
3000 VDCCRF (600)
4800 P2 (600)
1200 EFF (600)
3000 VDCCFF (600)

PAGE 1

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FTN 4.54614

SUBROUTINE WRITE 74/74 UPT=1

```

1  SUBROUTINE WRITE(A,B,AE,BE,M,IT)
   INTEGER FLAG
   COMMON/IND,FLAG,IPRAN,DEV
   COMMON/E/GAUS(1),S
   GO TO (10,30),M
10  WRITE(6,20) DEV
20  FORMAT(/,/,1X,43HREVERSE FAILURE CURVES AND DATA FOR DEVICE ,
   IAB)
30  GO TO 50
40  WRITE(6,40) DEV
50  FORMAT(/,/,1X,43HFORWARD FAILURE CURVES AND DATA FOR DEVICE ,
   IAB)
60  GO TO (60,90),FLAG
70  WRITE(6,70) A,GAUS(1)
80  WRITE(6,80) B,GAUS(2)
90  WRITE(6,100) AE,GAUS(3),BE
100  WRITE(6,110) IT,S
110  WRITE(6,120) A,B,GAUS(1),GAUS(2),GAUS(3),BE,IT,S
120  FORMAT(/,30X,17HA AND B FOUND IN ,13,11H ITERATIONS,
   I10X,19HMINIMUM OF STA,B)= ,IPEIS.8)
   RETURN
   END

```

CARD NR. SEVERITY DETAILS DIAGNOSIS OF PROBLEM

```

5  1  AN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.
13 1  AN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.

```

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS	DEF LINE	REFERENCES	RELOCATION
3 WRITE	1	20	27
VARIABLES	SN	TYPE	
0 A		REAL	F.P.
0 AE		REAL	F.P.
0 B		REAL	F.P.
0 BE		REAL	F.P.
3 DEV		REAL	A
1 FLAG		INTEGER	A
0 GAUS		REAL	E
0 IND		INTEGER	A
2 IPRAN		INTEGER	A
0 IT		INTEGER	F.P.

APPENDIX C

PAGE 2

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FIN 4.54414

74/74 OPT=1

SUPROUTINE WRITE

VARIABLES SN TYPE
O M INTEGER
3 S REAL

FILE NAMES
TAPE6 MODE
FMT

STATEMENT LABELS

14 10

50 20 FMT

17 30

63 40 FMT

21 50

31 60

77 70 FMT

115 80 FMT

37 90

134 100 FMT

156 110 FMT

RELOCATION
F.P.
E

REFS
REFS

WRITES

DEF LINE REFERENCES

6 5

7 6

10 5

11 10

13 9

14 2+13

15 14

18 17

21 13

22 21

25 24

MEMBERS - BIAS NAME(LENGTH)

0 IND (1)

3 DEV (1)

0 GAUS (3)

COMMON BLOCKS LENGTH

A 4

E 4

STATISTICS

PROGRAM LENGTH

CM LABELED COMMON LENGTH

1678 119

108 8

1 FLAG (1)

3 5 (1)

2 IPRAM (1)

59

2

PAGE

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FTN 4.5+414

74/74 DP7=1

SUBROUTINE PLOTT

[illegible]

SUBROUTINE	PLOTT	74/74	OPI=1	PTN	4,5+4,14	06/01/76	14,04,4,6
1115	73	CALL PWRITE(2,FTITLEA,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, IT,P2)				PLOT	116
1115	74	CALL PWRITE(2,FTITLEB,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, IT,P3)				PLOT	117
1115	75	IF(ISEM-EQ,2) GO TO 75				PLOT	118
1120	76	CALL PWRITE(1,FTITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	119
1120	77	IF(FLAG-EQ,1) GO TO 90				PLOT	120
1120	78	FTITLEB(1)=10H DEVICES				PLOT	121
1120	79	FTITLEB(2)=10H FORWARD				PLOT	122
1120	80	FTITLEB(3)=10H FAILURE				PLOT	123
1120	81	FTITLEB(4)=10H FIT TO				PLOT	124
1120	82	FTITLEB(5)=10H FIT TO				PLOT	125
1120	83	FTITLEB(6)=10H P=8*7*6*5*4*3*2*1				PLOT	126
1120	84	FTITLEB(7)=10H 1+8*7*6*5*4*3*2*1				PLOT	127
1120	85	FTITLEB(8)=10H 5				PLOT	128
1120	86	IF(ISEM-EQ,0) GO TO 83				PLOT	129
1120	87	CALL CHANGE(JNUM,XTITLE,YTITLE,TDOFF,PFF)				PLOT	130
1120	88	CALL PWRITE(2,FTITLEB,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, JT,P1)				PLOT	131
1120	89	IF(ISEM-EQ,1) GO TO 90				PLOT	132
1120	90	IF(FLAG-EQ,3) GO TO 90				PLOT	133
1120	91	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	134
1120	92	10 CONTINUE				PLOT	135
1120	93	IF(JNUM-EQ,0) GO TO 130				PLOT	136
1120	94	IF(J-EQ,2) RETURN				PLOT	137
1120	95	100 GO TO 1110,120,110,110,IPRAN				PLOT	138
1120	96	110 CALL PWRITE(1,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	139
1120	97	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	140
1120	98	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	141
1120	99	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	142
1120	100	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	143
1120	101	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	144
1120	102	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	145
1120	103	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	146
1120	104	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	147
1120	105	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	148
1120	106	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	149
1120	107	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	150
1120	108	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	151
1120	109	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	152
1120	110	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	153
1120	111	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	154
1120	112	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	155
1120	113	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	156
1120	114	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	157
1120	115	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	158
1120	116	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	159
1120	117	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	160
1120	118	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	161
1120	119	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	162
1120	120	CALL PWRITE(1,ETITLEF,XTITLE,YTITLE,BLANK,LEGEN,JNUM,TDOFF,PFF, 10,0,0)				PLOT	163

CARD NR.	SEVERITY	DETAILS	DIAGNOSIS OF PROBLEM
1	1	1	1
2	2	2	2
3	3	3	3
4	4	4	4
5	5	5	5
6	6	6	6
7	7	7	7
8	8	8	8
9	9	9	9
10	10	10	10
11	11	11	11
12	12	12	12
13	13	13	13
14	14	14	14
15	15	15	15
16	16	16	16
17	17	17	17
18	18	18	18
19	19	19	19
20	20	20	20
21	21	21	21
22	22	22	22
23	23	23	23
24	24	24	24
25	25	25	25
26	26	26	26
27	27	27	27
28	28	28	28
29	29	29	29
30	30	30	30
31	31	31	31
32	32	32	32
33	33	33	33
34	34	34	34
35	35	35	35
36	36	36	36
37	37	37	37
38	38	38	38
39	39	39	39
40	40	40	40
41	41	41	41
42	42	42	42
43	43	43	43
44	44	44	44
45	45	45	45
46	46	46	46
47	47	47	47
48	48	48	48
49	49	49	49
50	50	50	50
51	51	51	51
52	52	52	52
53	53	53	53
54	54	54	54
55	55	55	55
56	56	56	56
57	57	57	57
58	58	58	58
59	59	59	59
60	60	60	60
61	61	61	61
62	62	62	62
63	63	63	63
64	64	64	64
65	65	65	65
66	66	66	66
67	67	67	67
68	68	68	68
69	69	69	69
70	70	70	70
71	71	71	71
72	72	72	72
73	73	73	73
74	74	74	74
75	75	75	75
76	76	76	76
77	77	77	77
78	78	78	78
79	79	79	79
80	80	80	80
81	81	81	81
82	82	82	82
83	83	83	83
84	84	84	84
85	85	85	85
86	86	86	86
87	87	87	87
88	88	88	88
89	89	89	89
90	90	90	90
91	91	91	91
92	92	92	92
93	93	93	93
94	94	94	94
95	95	95	95
96	96	96	96
97	97	97	97
98	98	98	98
99	99	99	99
100	100	100	100

AN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.
AN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.

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APPENDIX C

SUBROUTINE PLOTT			74/74	OPT=1	FTN 4.5+414			06/01/76	14.04.49	PAGE	5
VARIABLES	SN	TYPE	RELOCATION								
3410 TDOCRF	REAL	ARRAY	C		152	154	158				
3410 TDOCRF	REAL	ARRAY	B		7	156					
1130 TDRF	REAL	ARRAY	B		5	147					
5670 VDOCRF	REAL	ARRAY	C		163	145		73	76	88	89
5670 VDOCRF	REAL	ARRAY	B		7	154					
1006 XTITLE	REAL	ARRAY			5	145					
					13	70	71	73	76		
					114	115	117	120	132	133	89
					143	149	152	154	158		137
1017 XTITLEP	REAL	ARRAY			15	20	21	22			
1011 YTITLE	REAL	ARRAY			13	147	156	DEFINED	15	31	32
1014 YTITLEE	REAL	ARRAY			13	70	71	73	88	69	114
					117	132	133	DEFINED	15	23	24
1030 YTITLEI	REAL	ARRAY			13	76	93	120	137		
1022 YTITLEZ	REAL	ARRAY			15	25	26				
1025 YTIIVDC	REAL	ARRAY			13	149	158	DEFINED	15	43	44
4540 ZFF	REAL	ARRAY			13	143	152	DEFINED	15	37	38
4540 ZRF	REAL	ARRAY	C		13	145	147	154	156		
					7	140	41	42			
					5	152					
					114	132					
					76	89		115	117	120	133
					145	147	149	152	154	156	158

EXTERNALS			TYPE	ARGS	REFERENCES
CHANGE				5	70
PWRITE				11	71
					137
					143

STATEMENT LABELS			DEF LINE	REFERENCES
0 20	INACTIVE		54	
66 30			55	2954
111 33			71	69
124 35			78	75
126 40			79	54
145 43			89	67
157 50			95	78
161 60			97	52
172 70			99	2998
215 73			115	113
230 75			122	119
232 80			123	98
251 83			133	131
263 90			139	53
0 100	INACTIVE		142	
277 110			143	3+142
315 120			152	142
332 130			161	97

COMMON BLOCKS			LENGTH	MEMBERS - BIAS NAME(LENGTH)
A	4			0 IND (11)
B	6000			3 DEV (11)
				0 PRF (100)
				1600 TDOCRF (600)
				3600 IPRF (600)
				5400 P3 (600)

1 FLAG (11)			2 IPRAM (11)
600 TDRF (600)			1200 ERF (600)
2400 ZRF (600)			3000 VDOCRF (600)
4200 P1 (600)			4600 P2 (600)

APPENDIX C

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FTN 4.5.414

74/74 OPT=1

SUBROUTINE PLUTT

COMMON BLOCKS LENGTH MEMBERS - BIAS NAME(LENGTH)
 C 4200 0 PFF (600)
 1800 TDCEFF (600)
 3600 IPFF (600)
 D 1200 0 T (600)
 F 3 0 IPLOT (1)

600 TDF (600)
 2400 ZFF (600)
 600 PP (600)
 1 ISEM (1)

1200 EFF (600)
 3000 VDCFF (600)

2 ITYPE (1)

STATISTICS

PROGRAM LENGTH 10418 545
 CM LABELED COMMON LENGTH 262178 11407

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FTN 4.5+14

SUBROUTINE ALSQAR 74/74 DPT=1

```

1 SUBROUTINE ALSQAR(N,A)
  REAL IPRF
  COMMON/B/PRF(600),TDRF(600),ERF(600),TDOCRF(600),ZRF(600),
  1 VDCRF(600),IPRF(600),PI(600),P2(600),P3(600)
  5 COMMON/D/T(600),PP(600)
  SUMTC=0.
  SUMCP=0.
  DO 10 I=1,N
    SUMTC=SUMTC+ALOG10(T(I))
    SUMCP=SUMCP+ALOG10(PP(I))
  10 CONTINUE
  ARG=(SUMTC+SUMCP)/N
  A=10.**ARG
  DO 20 I=1,N
    P2(I)=A*T(I)**(-1)
  20 RETURN
  END

```

```

2 ALSQAR
3 ALSQAR
4 ALSQAR
5 ALSQAR
6 ALSQAR
7 ALSQAR
8 ALSQAR
9 ALSQAR
10 ALSQAR
11 ALSQAR
12 ALSQAR
13 ALSQAR
14 ALSQAR
15 ALSQAR
16 ALSQAR
17 ALSQAR
18 ALSQAR

```

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS	DEF LINE	REFERENCES				
3 ALSQAR	1	16				
VARIABLES	SN	TYPE	RELOCATION	F.P.	REFS	
0 A		REAL			15	
53 ARG		REAL			13	
2260 ERF		REAL	ARRAY	B	3	
52 I		INTEGER			9	
7020 IPRF		REAL	ARRAY	B	2	
0 N		INTEGER		F.P.	8	
1130 PP		REAL	ARRAY	D	5	
0 PRF		REAL	ARRAY	B	8	
10150 P1		REAL	ARRAY	B	3	
111300 P2		REAL	ARRAY	B	3	
12430 P3		REAL	ARRAY	B	3	
51 SUMCP		REAL			10	
50 SUMTC		REAL			9	
0 T		REAL	ARRAY	D	5	
3410 TDOCRF		REAL	ARRAY	B	3	
1130 TDRF		REAL	ARRAY	B	3	
5670 VDCRF		REAL	ARRAY	B	3	
4540 ZRF		REAL	ARRAY	B	3	
EXTERNALS	TYPE	ARGS	REFERENCES			
ALOG10	REAL	1	LIBRARY	9	10	
STATEMENT LABELS	DEF LINE	REFERENCES				
0 10	11	8				
0 20	15	14				
LOOPS	LABEL	INDEX	FROM-TO	LENGTH	PROPERTIES	EXT REFS
20 10	* 1		8 11	11B		EXT REFS
40 20	* 1		14 15	6B		EXT REFS

APPENDIX C

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FTN 4.54414

74/74 OPT=1

SUBROUTINE ALSQAR

COMMON BLOCKS
B
LENGTH 6000
MEMBERS - BIAS NAME(LENGTH)
0 PRF (600)
1800 TDUCRF (600)
3600 IPRF (600)
5400 P3 (600)
0 T (600)

600 TDRF (600)
2400 ZRF (600)
4200 P1 (600)
600 PP (600)
1200 ERF (600)
3000 VDCRF (600)
4800 P2 (600)

STATISTICS
PROGRAM LENGTH 618 49
CM LABELED COMMON LENGTH 160408 7200

```

1      SUBROUTINE BLSQAR(N,B)
      REAL IPRF
      COMMON/8/PRF(600),TDRF(600),TDCRF(600),ZRF(600),
1      VDCRF(600),IPRF(600),PI(600),P2(600),P3(600)
      SUMTD=0.
      SUMDP=0.
      DO 10 I=1,N
      SUMTD=SUMTD+ALOG10(T(I))
      SUMDP=SUMDP+ALOG10(PP(I))
10     CONTINUE
      ARG=(SUMDP+.5*SUMTD)/N
      B=10.**ARG
      DO 20 I=1,N
      P3(I)=B*T(I)**(-.5)
20     RETURN
      END

```

```

      BLSQAR 2
      BLSQAR 3
      BLSQAR 4
      BLSQAR 5
      BLSQAR 6
      BLSQAR 7
      BLSQAR 8
      BLSQAR 9
      BLSQAR 10
      BLSQAR 11
      BLSQAR 12
      BLSQAR 13
      BLSQAR 14
      BLSQAR 15
      BLSQAR 16
      BLSQAR 17
      BLSQAR 18

```

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS	DEF LINE	REFERENCES	SN	TYPE	RELOCATION	REFS	13	12	11	10	9	8	7	6	5	4	3	2	1	14
3 BLSQAR	1	16																		
VARIABLES																				
55 ARG	REAL																			
0 B	REAL																			
2260 ERF	REAL																			
54 I	INTEGER																			
7020 IPRF	REAL																			
0 N	INTEGER																			
1130 PP	REAL																			
0 PRF	REAL																			
10150 P1	REAL																			
11300 P2	REAL																			
12430 P3	REAL																			
53 SUMDP	REAL																			
52 SUMTD	REAL																			
0 T	REAL																			
3410 TDCRF	REAL																			
1130 TDRF	REAL																			
5670 VDCRF	REAL																			
4540 ZRF	REAL																			
EXTERNALS																				
ALOG10	REAL																			
STATEMENT LABELS																				
0 10																				
0 20																				
LOOPS LABEL																				
20 10																				
40 20																				
INDEX																				
* 1																				
FROM-TO																				
8 11																				
14 15																				
LENGTH																				
118																				
68																				
PROPERTIES																				
EXT REFS																				
EXT REFS																				

APPENDIX C

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74/74 OPT=1

SUBROUTINE BLSQR

COMMON BLOCKS LENGTH MEMBERS - BIAS NAME(LENGTH)
 B 6000 0 PRF (600)
 1800 TODCRF (600)
 3600 IPRF (600)
 5400 P3 (600)
 D 1200 0 T (600)

STATISTICS

PROGRAM LENGTH 638 51
 CN LABELED COMMON LENGTH 160408 7200

600 TORF (600)
 2400 IZF (600)
 4200 P1 (600)
 600 PP (600)

1200 ERF (600)
 3000 YDCRF (600)
 4800 P2 (600)

SUBROUTINE ABLSGAR 74/74 OPT=1
 1 SUBROUTINE ABLSGAR(N,AI,BI,AE,BE,IT)
 REAL IPRF
 COMMON/IND,FLAG,IPRAM,DEV
 COMMON/B/PRF(600),TDRF(600),ERF(600),TDOCRF(600),ZRF(600),
 5 VCKRF(600),IPRF(600),P1(600),P2(600),P3(600),
 COMMON/D/T(600),PP(600)
 COMMON/E/CAUS(3),S
 DIMENSION A(500),B(500)
 10 I=1
 J=1
 EPS=1.E-4
 A(I)=AI
 B(I)=BI
 15 L=0
 SI=SAB(N,A(I),B(I))
 AI=A(I)/(2.,+J)
 BI=B(I)/(2.,+J)
 IF(SAB(N,A(I+1),B(I+1)).LT.SI) GO TO 20
 A(I+1)=A(I)+AI
 B(I+1)=B(I)+BI
 20 IF(SAB(N,A(I+1),B(I+1)).LT.SI) GO TO 20
 A(I+1)=A(I)
 GO TO 30
 25 L=L+1
 BI=B(I)/(2.,+J)
 B(I+1)=B(I)+BI
 IF(SAB(N,A(I+1),B(I+1)).LT.SI) GO TO 40
 B(I+1)=B(I)+BI
 30 IF(SAB(N,A(I+1),B(I+1)).LT.SI) GO TO 40
 B(I+1)=B(I)
 GO TO 50
 35 L=L+1
 IF(L.EQ.1) GO TO 60
 J=J+1
 IF(J.GT.20) GO TO 90
 J=J+1
 GO TO 10
 40 S=SAB(N,A(I+1),B(I+1))
 ERR=ABS(S-SI)
 IF(ERR.LT.EPS) GO TO 70
 J=J+1
 GO TO 10
 45 AE=A(I+1)
 BE=B(I+1)
 IT=I
 DO 80 I=1,N
 80 PI(I)=AE*OT(1)+(-1)*BE*OT(1)+(-.5)
 GO TO 110
 90 WRITE(6,100)
 100 FORMAT(/,/,IX,4IHNBER OF ITERATIONS FOR 2**J EXCEED J=20)
 50 RETURN
 END

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ABLSGAR 2
 ABLSGAR 3
 ABLSGAR 4
 ABLSGAR 5
 ABLSGAR 6
 ABLSGAR 7
 ABLSGAR 8
 ABLSGAR 9
 ABLSGAR 10
 ABLSGAR 11
 ABLSGAR 12
 ABLSGAR 13
 ABLSGAR 14
 ABLSGAR 15
 ABLSGAR 16
 ABLSGAR 17
 ABLSGAR 18
 ABLSGAR 19
 ABLSGAR 20
 ABLSGAR 21
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 ABLSGAR 42
 ABLSGAR 43
 ABLSGAR 44
 ABLSGAR 45
 ABLSGAR 46
 ABLSGAR 47
 ABLSGAR 48
 ABLSGAR 49
 ABLSGAR 50
 ABLSGAR 51
 ABLSGAR 52

APPENDIX C

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FTN 4.54414

SUBROUTINE ABLSOAR 74/74 OPT=1

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS DEF LINE REFERENCES

3 ABLSOAR 1 50

VARIABLES SN TYPE RELOCATION

213 A		REAL	ARRAY		REFS	8	15	16	17	18	19	20
					26	28	37	42	DEFINED	12	17	
0 AF		REAL			21							
0 AI		REAL		F.P.	46	DEFINED	1	42				
210 A1		REAL		F.P.	12	DEFINED	1					
1177 B		REAL	ARRAY		17	19	DEFINED	16	20	25	26	
					8	15	18	20	24	13	25	
					27	29	37	43	DEFINED			
0 BE		REAL			27							
0 BI		REAL		F.P.	46	DEFINED	1	43				
211 B1		REAL		F.P.	13	DEFINED	1					
3 DEV		REAL			25	27	DEFINED	24				
205 EPS		REAL		A	3							
2260 ERF		REAL	ARRAY	B	39	DEFINED	11					
212 ERR		REAL			4							
1 FLAG		REAL			39	DEFINED	38					
0 GAUS		REAL	ARRAY	A	3							
203 I		INTEGER		E	7							
					REFS	12	2015	16	2017	2018	2019	
					2020	2021	2025	2026	2027	2028	2029	
					33	40	42	43	44	3046		
0 IND		INTEGER		A	9	33	40	45				
2 IPARM		INTEGER		B	3							
7020 IPRF		REAL	ARRAY		REFS	4						
0 IT		INTEGER		F.P.	2							
204 J		INTEGER			REFS	44						
206 L		INTEGER			16	24	34	35	DEFINED	10	35	
0 N		INTEGER		F.P.	32	DEFINED	14	23	31	37	45	
					REFS	15	20	26	28			
1130 PP		REAL	ARRAY	D	DEFINED	1						
0 PRF		REAL			REFS	6						
10150 P1		REAL	ARRAY	B	REFS	4						
11300 P2		REAL	ARRAY	B	REFS	4	46					
12430 P3		REAL	ARRAY	B	REFS	4						
3 S		REAL	ARRAY	E	REFS	4						
207 S1		REAL			REFS	7						
					REFS	18	DEFINED	37	38			
0 T		REAL	ARRAY	D	REFS	20	26	28				
3410 TOOCRF		REAL	ARRAY	B	DEFINED	15						
1130 TDRF		REAL	ARRAY	B	REFS	6	2046					
5070 VDCRF		REAL	ARRAY	B	REFS	4						
4560 ZRF		REAL	ARRAY	B	REFS	4						
FILE NAMES		MODE										
TAPF6		FMT		WRITES	48							
EXTERNALS		TYPE	ARGS	REFERENCES	15							
SAB		REAL	3	18	20	26	28	37				

SUBROUTINE ABLSQAR 74/74 OPT=1
 INLINE FUNCTIONS TYPE ARGCS DEF LINE REFERENCES
 ABS 1 INTRIN 38
 STATEMENT LABELS
 23 10 14 36 41
 60 20 23 18 20
 61 30 24 22
 110 40 31 26 28
 111 50 32 30
 117 60 37 32
 133 70 42 39
 0 80 46 45
 154 90 48 34
 170 100 FMT 49 48
 156 110 50 47
 LOOPS LABEL INDEX FROM-TO LENGTH PROPERTIES EXT REFS
 141 80 1 45 46 138
 COMMON BLOCKS LENGTH MEMBERS - BIAS NAME(LENGTH)
 A 4 0 IND (1) 1 FLAG (1)
 B 6000 3 DEV (1) 600 TDRF (600)
 1800 TDCRF (600) 1200 ERF (600)
 3600 IPRF (600) 3000 VOCRF (600)
 5400 P3 (600) 4200 P1 (600)
 0 T (600) 600 PP (600)
 0 GAUS (3) 3 S (1)
 D 1200 4
 E 4
 STATISTICS
 PROGRAM LENGTH 21778 1151
 CM LABELED COMMON LENGTH 160508 7208

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FIN 4.54414

SUBROUTINE PWRITE 74/74 OPT=1

```

1 SUBROUTINE PWRITE(N,I,XT,YT,GLD,CLL,N,X,Y,XX,YY)
2 COMMON/FPLOT,ISEM,I,TYPE
3 DIMENSION XT(600),YT(600),XX(600),YY(600)
4 DIMENSION I(8),XT(3),YT(3),GLD(3),CLL(3)
5 IF(I,TYPE.EQ.1) GO TO 10
6 CALL SELPLOT(I,PLPLOT)
7 CALL TALCGRAP(X,0.,0.,0.,0.,0.,0.,I,XT,YT)
8 CALL TALDATA(N,X,Y,I,2,CLD)
9 IF(K,EQ.1) RETURN
10 CALL TALDATA(N,XX,YY,I,1,CLL)
11 RETURN
12 CONTINUE
13 CALL DRAW4(I,7,3,3,3,6,XT,YT,CLL,T)
14 CALL DRAW4(2,7,2,N,-2,10,X,Y,0.,0.)
15 IF(K,EQ.1) GO TO 20
16 CALL DRAW4(2,7,2,N,0,10,XX,YY,0.,0.)
17 CALL DRAW4(3,7,2,0,2,N,XX,YY,2.,0.)
18 RETURN
19 END
20

```

SYMBOLIC REFERENCE MAP (R=3)

[illegible]

APPENDIX C

SUBROUTINE PWRITE 74/74 OPT=1 PAGE 2
 COMMON BLOCKS LENGTH 3 MEMBERS - BIAS NAME(LENGTH)
 F 0 IPLOT (1)

STATISTICS
 PROGRAM LENGTH 2208 144
 CM LABELED COMMON LENGTH 38 3

FTN 4.5+414
 1 ISEM (1) 2 ITYPE (1)

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APPENDIX C

PAGE 1

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FTN 4.5+414

74/74 DPT=1

SUBROUTINE SORT

```

1  SUBROUTINE SORT(IN)
COMMON/D/T(600),PPI(600)
DIMENSION E(600),H(600)
J=1
10  TOMIN=L.E300
DO 20 L=1,N
TOMIN=AMIN1(TOMIN,T(L))
IF(TOMIN.EQ.T(L)) J=L
20  CONTINUE
IF(TOMIN.GT.L.E50) GO TO 40
E(J)=PP(J)
H(J)=TOMIN
J=J+1
T(J)=L.E51
GO TO 10
40  CONTINUE
DO 50 L=1,N
PP(L)=E(L)
T(L)=H(L)
50  CONTINUE
RETURN
END

```

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS	DEF LINE	REFERENCES	DEF LINE	REFERENCES
3 SORT	1	22		
VARIABLES	SN	TYPE	RELOCATION	REFS
51 E	REAL	ARRAY		3
1201 H	REAL	ARRAY		3
45 I	INTEGER			12
46 J	INTEGER			12
50 L	INTEGER			8
0 N	INTEGER			7
1130 PP	REAL	ARRAY	F.P.	REFS
0 T	REAL	ARRAY	D	REFS
47 TOMIN	REAL	ARRAY	D	REFS
INLINE FUNCTIONS	TYPE	ARGS	DEF LINE	REFERENCES
AMIN1	REAL	0	INTRIN	8
STATEMENT LABELS	DEF LINE	REFERENCES		
7 10	6	16		
0 20	10	7		
32 40	17	11		
0 50	21	18		
LOOPS LABEL	INDEX	FROM-TO	LENGTH	PROPERTIES
13 20	L	7 10	68	INSTACK
35 50	L	16 21	48	INSTACK

APPENDIX C

SUBROUTINE SORT	74/74	DPT=1	FTN 4.5+414	06/01/76	14.04.49	PAGE	2
COMMON BLOCKS	LENGTH	MEMBERS - BIAS NAME(LENGTH)	600 PP				
D	1200	O T (600)	(600)				
STATISTICS							
PROGRAM LENGTH	23318	1241					
CM LABELED COMMON LENGTH	22608	1200					


```

1 SUBROUTINE GOODFIT(Y,V1,N,M,J)
  INTEGER FLAG
  COMMON/A/IND,FLAG,IPRAM,DEV
  COMMON/E/KAUS(3),S
  DIMENSION Y(600),Y1(600)
  IF(FLAG.EQ.2) RETURN
  SUM=0.
  DO 10 I=1,N
    Y1=ALOG10(Y(I))
    Y1=ALOG10(Y1(I))
    SUM=SUM+(Y1-Y1L)*o2
  10 CONTINUE
  GO TO (20,30,40),J
  20 KAUS(1)=SUM/(N-M)
    RETURN
  30 KAUS(2)=SUM/(N-M)
    RETURN
  40 KAUS(3)=SUM/(N-M)
    RETURN
  END

```

CARD NR.	SEVERITY	DETAILS	DIAGNOSIS OF PROBLEM
1	1	1	1
2	2	2	2
3	3	3	3
4	4	4	4
5	5	5	5
6	6	6	6
7	7	7	7
8	8	8	8
9	9	9	9
10	10	10	10
11	11	11	11
12	12	12	12
13	13	13	13
14	14	14	14
15	15	15	15
16	16	16	16
17	17	17	17
18	18	18	18
19	19	19	19
20	20	20	20
21	21	21	21
22	22	22	22
23	23	23	23
24	24	24	24
25	25	25	25
26	26	26	26
27	27	27	27
28	28	28	28
29	29	29	29
30	30	30	30
31	31	31	31
32	32	32	32
33	33	33	33
34	34	34	34
35	35	35	35
36	36	36	36
37	37	37	37
38	38	38	38
39	39	39	39
40	40	40	40
41	41	41	41
42	42	42	42
43	43	43	43
44	44	44	44
45	45	45	45
46	46	46	46
47	47	47	47
48	48	48	48
49	49	49	49
50	50	50	50
51	51	51	51
52	52	52	52
53	53	53	53
54	54	54	54
55	55	55	55
56	56	56	56
57	57	57	57
58	58	58	58
59	59	59	59
60	60	60	60
61	61	61	61
62	62	62	62
63	63	63	63
64	64	64	64
65	65	65	65
66	66	66	66
67	67	67	67
68	68	68	68
69	69	69	69
70	70	70	70
71	71	71	71
72	72	72	72
73	73	73	73
74	74	74	74
75	75	75	75
76	76	76	76
77	77	77	77
78	78	78	78
79	79	79	79
80	80	80	80
81	81	81	81
82	82	82	82
83	83	83	83
84	84	84	84
85	85	85	85
86	86	86	86
87	87	87	87
88	88	88	88
89	89	89	89
90	90	90	90
91	91	91	91
92	92	92	92
93	93	93	93
94	94	94	94
95	95	95	95
96	96	96	96
97	97	97	97
98	98	98	98
99	99	99	99
100	100	100	100

AN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS	DEF LINE	REFERENCES	15	17	19
3 GOODFIT	1	6			
VARIABLES	SN	TYPE	RELOCATION		
3 DEV	REAL		A	REFS	3
1 FLAG	INTEGER		A	REFS	2
0 GAUS	REAL	ARRAY	E	REFS	4
60 I	INTEGER			REFS	4
0 FMD	INTEGER		A	REFS	9
2 IPARM	INTEGER		A	REFS	3
0 J	INTEGER			REFS	3
0 M	INTEGER		F.P.	REFS	13
0 N	INTEGER		F.P.	REFS	14
3 S	REAL		F.P.	REFS	8
57 SUM	REAL		E	REFS	4
0 Y	REAL			REFS	11
0 VI	REAL	ARRAY	F.P.	REFS	5
62 YIL	REAL	ARRAY	F.P.	REFS	5
61 YL	REAL			REFS	11
EXTERNALS	TYPE	ARC	REFERENCES		
ALOG10	REAL	1 LIBRARY	9		10

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FTN 4.5+414

74/74 OPT=1

SUBROUTINE GOODFIT

STATEMENT LABELS

DEF LINE REFERENCES

0	10	8
12	20	13
14	30	13
16	40	13
18		

LOOPS LABEL INDEX FROM-TO LENGTH PROPERTIES

EXT REFS

21	10	8	12	128
----	----	---	----	-----

COMMON BLOCKS LENGTH MEMBERS - BIAS NAME(LENGTH)

A	4	0 IND (1)
E	4	3 DEV (1)
		0 GAUS (3)

2 IPRAH (1)

1 FLAG (1)

3 S (1)

STATISTICS

PROGRAM LENGTH

CM LABELED COMMON LENGTH

758	61
108	8

```

1 SUBROUTINE GAUSS
2 INTEGER FLAG
3 COMMON/A/IND, FLAG, IPRAM, DEV
4 COMMON/E/GAUSS(3), S
5 J=3
6 IF(FLAG.EQ.2) RETURN
7 IF(FLAG.EQ.1) J=2
8 GMIN=1.E300
9 DO 10 I=1, J
10 GMIN=AMIN1(GMIN, GAUSS(I))
11 CONTINUE
12 DO 15 I=1, J
13 IF(GMIN.EQ.GAUSS(I)) L=I
14 CONTINUE
15 WRITE(6, 20)
20 FORMAT(/,/, 5X, 34HGAUSS CRITERION OF GOODNESS OF FIT,/, 10X,
134HTHE EQUATION WHICH BEST FITS THIS DATA IS: )
21 GO TO (30, 50, 70), L
22 WRITE(6, 40)
30 FORMAT(/, 30X, 11HP=A*100(-1))
31 RETURN
32 WRITE(6, 60)
50 FORMAT(/, 30X, 12HP=B*100(-.5))
60 RETURN
61 WRITE(6, 80)
70 FORMAT(/, 30X, 22HP=A*100(-1)+B*100(-.5))
80 RETURN
90 END

```

UN IF STATEMENT MAY BE MORE EFFICIENT THAN A 2 OR 3 BRANCH COMPUTED GO TO STATEMENT.

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS 1 GAUSS	DEF LINE 1	REFERENCES 6	21	24	27
VARIABLES	SN	TYPE	RELOCATION		
3 DEV	REAL		A	REFS	3
1 FLAG	INTEGER		A	REFS	2
0 GAUS	REAL	ARRAY	E	REFS	4
117 GMIN	REAL			REFS	10
120 I	INTEGER			REFS	10
C IND	INTEGER		A	REFS	3
2 IPRAM	INTEGER		A	REFS	3
116 J	INTEGER			REFS	9
121 L	INTEGER			REFS	10
3 S	REAL		E	REFS	4

SUBROUTINE GAUSS 74/74 OPT-1 FTN 4.5+414 06/01/76 14.04.49 PAGE 2
 FILE NAMES MODE
 TAPE6 FMT
 INLINE FUNCTIONS TYPE ARGS DEF LINE REFERENCES
 AMINI REAL 0 INTRIN 10
 WRITES 15 19 22 25
 STATEMENT LABELS
 0 10 11 9
 1 15 14 12
 55 20 FMT 16 15
 41 30 19 18
 73 40 FMT 20 19
 44 50 22 18
 101 60 FMT 23 22
 47 70 25 18
 110 80 FMT 26 25
 LOOPS LABEL INDEX FROM-TO LENGTH PROPERTIES
 13 10 1 9 11 48 INSTACK
 22 15 1 12 14 48 INSTACK
 COMMON BLOCKS LENGTH MEMBERS - BIAS NAME(LENGTH)
 A 4 0 IND (1)
 E 4 3 DEV (1)
 0 GAUS (3)
 1 FLAG (1) 2 IPRAH (1)
 3 S (1)
 STATISTICS
 PROGRAM LENGTH 1228 82
 CM LABELED COMMON LENGTH 108 8

FUNCTION SAB

SYMBOLIC REFERENCE MAP (R=3)

[illegible]

EXTERNALS	ALOGIO	TYPE	ARCS	REFERENCES	11
		REAL	1 LIBRARY	10	
STATEMENT LABELS			DEF LINE	REFERENCES	
0 10			13	7	
LOOPS LABEL	INDEX		FROM-TO	LENGTH	PROPERTIES
15 10	* 1		7 13	258	EXT REFS
COMMON BLOCKS	LENGTH				
D	1200				
			MEMBERS -	BIAS NAME(LENGTH)	
			0 7	(600)	60

STATISTICS	
PROGRAM LENGTH	618 49
CM LABELED COMMON LENGTH	22608 1200

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FTN 4.5+414

SUBROUTINE DWNDAT 74/74 GPT=1

```

1 SUBROUTINE OUNDAT(NUMB)
2   REAL JUNC,MAN1,MAN2
3   COMMON/ A/ IND,FLAG,IPRAN,DEV
4   COMMON/ D/ T16001,PP(600)
5   COMMON/ F/ IPLDT,ISEM,ITYPE
6   COMMON/ G/ DEVTP1,DEVTP2,JUNC,MAN1,MAN2,TECH,DATEE,ISTOP
7   READ(5,10) IIDENT1,IIDENT2,XLAB,YLAB
8   FORMAT(2A10,10X,A10,10X,A10)
9   DO 30 I=1,NUMB
10    READ(5,20) T(1),PP(1)
11    FORMAT(2E10,3)
12    CONTINUE
13  IF(ISTOP.EQ.3) GO TO 85
14  WRITE(6,40) DEV,DEVTP1,DEVTP2,JUNC,MAN1,MAN2,TECH,DATEE
15  FORMAT(5X,8HDEVICE: A8,3X,13HDEVICE TYPE: A2A10,/,/,
16  A10HJUNCTION: A9,/,5X,14HMANUFACTURER: A2A10,3X,12HTECHNICIAN: A
17  A10,3X,6HDATE: A10,/,/)
18  WRITE(6,50) IIDENT1,IIDENT2
19  FORMAT(5X,14HIDENTIFICATION: A2A10,/,/)
20  WRITE(6,60) XLAB,YLAB,XLAB,YLAB,XLAB,YLAB
21  FORMAT(3A11X,A10,5X,A10)
22  WRITE(6,70)
23  FORMAT(3(11X,25(1H-)))
24  CALL COLMNS(NUMB,T,PP)
25  WRITE(6,80)
26  FORMAT(1H1)
27  CONTINUE
28  IF(IND.EQ.2) GO TO 90
29  CALL DIRECT(NUMB,3,A,B,AE,BE,IT)
30  CALL WRITE(A,B,AE,BE,I,IT)
31  CALL GAUSS
32  IF(ISTOP.EQ.1) GO TO 88
33  CALL PLOTT(NUMB,NUMB,I)
34  IF(IND.EQ.1) GO TO 100
35  CONTINUE
36  CALL DIRECT(NUMB,3,A,B,AE,BE,IT)
37  CALL WRITE(A,B,AE,BE,2,IT)
38  CALL GAUSS
39  IF(ISTOP.EQ.1) GO TO 100
40  CALL PLOTT(NUMB,NUMB,2)
41  CONTINUE
42  RETURN
43  END
44

```

SYMBOLIC REFERENCE MAP (R=3)

ENTRY POINTS	DEF LINE	REFERENCES
3 QWNDAT	1	42

VARIABLES	SN	TYPE	RELOCATION
267 A		REAL	
271 AF		REAL	
270 B		REAL	

REFS	29	30	36	37
REFS	29	30	36	37
REFS	29	30	36	37

APPENDIX C

SUBROUTINE OHNDAT				74/74	DPT-1	FTN 4.5*4.14				06/01/76	14.04.49	PAGE	2
VARIABLES	SN	TYPE	RELOCATION										
272 BE	REAL												
6 DATEE	REAL		G										
3 DEV	REAL		A										
0 DEVTP1	REAL		G										
1 DEVTP2	REAL		G										
1 FLAG	REAL		A										
266 I	INTEGER												
262 IDENT1	INTEGER												
263 IDENT2	INTEGER												
0 IND	INTEGER		A										
0 IPLOT	INTEGER		F										
2 IPRAM	INTEGER		A										
1 ISEN	INTEGER		F										
7 ISTOP	INTEGER		G										
273 IT	INTEGER												
2 ITYPE	INTEGER		F										
2 JUNC	REAL		G										
3 MAN1	REAL		G										
4 MAN2	REAL		G										
0 NUMB	INTEGER		F.P.										
1130 PP	REAL		ARRAY										
0 T	REAL		ARRAY										
5 TECH	REAL		D										
264 XLAB	REAL		G										
265 YLAB	REAL												
FILE NAMES	MODE												
TAPE5	FMT												
TAPE6	FMT												
EXTERNALS	TYPE	ARGS	REFERENCES	READS	WRITES								
COLUMNS													
DIRECT		3	24										
GAUSS		7	29										
PLOTT		0	31										
WRITE		3	33										
		6	30										
STATEMENT LABELS	DEF LINE	REFERENCES											
154 10	FMT	8	7										
165 20	FMT	11	10										
0 30		12	9										
202 40	FMT	15	14										
224 50	FMT	19	18										
241 60	FMT	21	20										
247 70	FMT	23	22										
255 80	FMT	26	25										
47 85		27	13										
64 88		34	32										
66 90		35	28										
101 100		41	34										
LOOPS LABEL	INDEX	FROM-TO	LENGTH	PROPERTIES	EXT REFS								
20 30	* 1	9 12	118										

APPENDIX C

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FTN 4.5+414 06/01/76 14.04.49

1 FLAG (1)	2 IPRAM (1)
600 PP (600)	
1 ISEM (1)	2 ITYPE (1)
1 DEVTP2(1)	2 JUNC (1)
4 MAN2 (1)	5 TECH (1)
7 ISTOP (1)	

SUBROUTINE DWDAT 74/74 OPT=1

COMMON BLOCKS	LENGTH	MEMBERS - BIAS NAME(LENGTH)
A	4	0 IND (1)
		3 DEV (1)
D	1200	0 T (600)
F	3	0 IPLOT (1)
G	8	0 DEVTP1(1)
		3 MAN1 (1)
		6 DATEE (1)

STATISTICS

PROGRAM LENGTH	2768	190
CM LABELED COMMON LENGTH	22778	1215


```

1  SUBROUTINE COLMNS(KPTS,X,Y)
2  DIMENSION X(1),Y(1)
3  INC=KPTS/3
4  IK=MOD(KPTS,3)
5  ICOL=INC+1
6  IF(IK.EQ.0) GO TO 50
7  IF(IK.EQ.1) GO TO 50
8  IF(IK.EQ.2) GO TO 70
9  IF(IK.EQ.3) GO TO 80
10 WRITE(6,60) X(1),Y(1),X(1+INC),Y(1+INC),X(1+2*INC),Y(1+2*INC),
11 I=1,INC
12 GO TO 90
13 FORMAT(3(11X,1PE11.3,3X,1PE11.3))
14 GO TO 90
15 WRITE(6,60) X(1),Y(1),X(1+ICOL),Y(1+ICOL),X(1+2*ICOL-1),
16 Y(1+2*ICOL-1),I=1,INC
17 WRITE(6,60) X(ICOL),Y(ICOL)
18 GO TO 90
19 WRITE(6,60) X(1),Y(1),X(1+ICOL),Y(1+ICOL),X(1+2*ICOL),
20 Y(1+2*ICOL),I=1,INC
21 WRITE(6,60) X(ICOL),Y(ICOL),X(2*ICOL),Y(2*ICOL)
22 CONTINUE
23 RETURN
24 END

```

ENTRY POINTS	DEF LINE	REFERENCES
3 COLUMNS	1	21

VARIABLES	SN	TYPE	RELOCATION	6*9	6*13	6*17	DEFINED	9	13	17
230 I		INTEGER		4*13	2*15	4*17	4*19	DEFINED	5	
227 ICOL		INTEGER		6	7	8	DEFINED	4		
226 IK		INTEGER		5	5*9	13	17	DEFINED	3	
225 INC		INTEGER		3	4	DEFINED	1			
0 KPIS		INTEGER	F.P.	2	3*9	3*13	15	3*17	2*19	
0 X		REAL	F.P.	1						
0 Y		REAL	F.P.	1	3*9	3*13	15	3*17	2*19	
				1						

FILE NAMES	MODE	WRITES	DEF LINE	REFERENCES
TAPE6	FMT			
INLINE FUNCTIONS	TYPE	ARGS	INTRIN	
MOD	INTEGER	2		6

STATEMENT LABELS	DEF LINE	REFERENCES
0 40	3	
26 50	9	6
157 60	11	9
52 70	13	7
105 80	17	8
142 90	20	12
	INACTIVE	
FMT		

APPENDIX C

PAGE 2

06/03/76 16.06.49

FTN 4.5.414

DPT=1

74/74

SUBROUTINE COLMNS

LOOPS	LABEL	INDEX	FROM-TO	LENGTH	PROPERTIES
31		* 1	9 9	178	EXT REFS
55		* 1	13 13	178	EXT REFS
110		* 1	17 17	178	EXT REFS
STATISTICS					
PROGRAM LENGTH					2576 175

```

SUBROUTINE CHANGE (NUMB, XLAB, YLAB, X, Y)
COMMON/D/ T(600), PP(600)
DIMENSION XTITLE(3), YTITLE(13), X(1600), Y(600)
DIMENSION XLAB(3), YLAB(13)
DATA XTITLE/3*1H /, YTITLE/3*1H /
XTITLE(4)=5H
XTITLE(12)=10PULSE MIDT
XTITLE(13)=10MH
YTITLE(1)=10H
YTITLE(2)=10HPOWER
DO 5 I=1,3
  XLAB(I)=XTITLE(I)
  YLAB(I)=YTITLE(I)
5 CONTINUE
DO 10 J=1, NUMB
  X(J)=T(J)
  Y(J)=PP(J)
10 CONTINUE
RETURN
END

```

SYMBOLIC REFERENCE MAP (R=3)

[illegible]

APPENDIX D.--SAMPLE INPUT WHEN ISEM = 0

Sample input data are listed when all of the data in card sets 3 and 4 are used.

APPENDIX D

```

*****
1      2      3      4      5      6      7      8
*****

```

1	3	2	1	1
10IN3600 0100F		C-A	FAIRCHILD	K. PARSONS 7-23-73
03IN3600				
00101 10.000E-6	100.	100.	0. 10.000E-6	1.0
1.0 160.	160.	0.00E	0.00E C+	
00102 10.000E-6	110.	105.	.15 10.000E-6	1.0
1.0 160.	160.	0.00E	0.00E C+	
00103 10.000E-6	120.	115.	.60 2.2 E-6	1.0
0. 160.	0.	0.00E	0.00E C+	
06IN3600				
00201 10.000E-6	60.000	60.	0.000 10.000E-6	.300
.300 92.	92.	0.00E	0.00E C+	
00202 10.000E-6	70.	70.	0. 10. E-6	.3
.3 92.	92.	. E	. E C+	
00203 10. E-6	80.	80.	0. 10. E-6	0.3
.3 92.	92.	. E	. E C+	
00204 10. E-6	90.	90.	0. 10. E-6	0.2
0.3 92.	92.	. E	. E C+	
00205 10. E-6	100.	80.	1.3 2.0 E-6	.3
.3 92.	92.	. E	. E C+ BRKOWN NG VZ CHG	
00206 10. E-6	110.	90.	2.2 .8 E-6	.3
.3 92.	4.	. E	. E C+	
03IN3600				
00301 10. E-6	90.	90.	0.0 10. E-6	.3
.3 90.	90.	. E	. E C+	
00302 10. E-6	90.	90.	0. 10. E-6	.3
.3 90.	90.	. E	. E C+	
00303 10. E-6	100.	95.	0.7 3.0 E-6	.3
.3 90.	0.	. E	. E C+	
04IN3600				
00401 10. E-6	80.	80.	0.0 10.0 E-6	.3
.3 98.	98.	. E	. E C+	
00402 10. E-6	90.	90.	0.0 10. E-6	.3
.3 98.	98.	. E	. E C+	
00403 10. E-6	100.	100.	0.0 10. E-6	.3
.3 98.	98.	. E	. E C+	
00404 10. E-6	110.	105.	1.0 1.9 E-6	.3
.3 98.	0.	. E	. E C+	
03IN3600				
00501 10. E-6	80.	80.	0.0 10.0 E-6	.3
.3 86.	86.	. E	. E C+	
00502 10. E-6	90.	85.	.6 1.2 E-6	.3
.3 86.	83.	. E	. E C+ BRKOWN DEVICE NU CG	
00503 10. E-6	100.	90.	1.8 1.2 E-6	.3
.3 86.	12.	. E	. E C+	
03IN3600				
00601 10. E-6	90.	80.	0.0 10. E-6	.3
.3 86.	86.	. E	. E C+	
00602 10. E-6	90.	90.	0.0 10. E-6	.3
.3 86.	86.	. E	. E C+	
00603 10. E-6	100.	90.	1.0 1.2 E-6	.3
.3 86.	0.0	. E	. E C+	

APPENDIX D

```

.....
1      2      3      4      5      6      7      8
.....

```

```

041N3600
00701 10.  E-6  80.   30.   .  E  0.0  10.  E-6  .3
      .3    86.   86.   .  E  .  E  C+
00702 10.  E-6  90.   90.   .  E  0.0  10.  E-6  .3
      .3    86.   86.   .  E  .  E  C+
00703 10.  E-6  100.  95.   .  E  .4  2.7  E-6  .3
      .3    86.   86.   .  E  .  E  C+
00704 10.  E-6  100.  90.   .  E  1.2  .8  E-6  .3
      .3    86.   17.   .  E  .  E  C+
051N3600
00801 10.  E-6  80.   80.   .  E  0.0  10.  E-6  .3
      .3    88.   88.   .  E  .  E  C+
00802 10.  E-6  90.   90.   .  E  0.0  10.  E-6  .3
      .3    88.   88.   .  E  .  E  C+
00803 10.  E-6  100.  100.  .  E  0.0  10.0  E-6  .3
      .3    88.   88.   .  E  .  E  C+
00804 10.  E-6  110.  110.  .  E  0.0  10.  E-6  .3
      .3    88.   88.   .  E  .  E
00805 10.  E-6  118.  105.  .  E  1.2  1.0  E-6  .3
      .3    88.   10.   .  E  .  E  C+
041N3600
00901 5.0  E-6  80.   80.   .  E  0.0  5.0  E-6  .3
      .3    93.   93.   .  E  .  E  C+
00902 5.0  E-6  90.   90.   .  E  0.0  5.0  E-6  .3
      .3    93.   93.   .  E  .  E  C+
00903 5.0  E-6  100.  95.   .  E  .6  2.8  E-6  .3
      .3    93.   93.   .  E  .  E  C+
00904 5.0  E-6  112.  100.  .  E  .9  .9  E-6  .3
      .2    93.   0.0   .  E  .  E  C+
041N3600
01001 5.0  E-6  80.   80.   .  E  0.0  5.0  E-6  .3
      .3    93.   93.   .  E  .  E  C+
01002 5.0  E-6  90.   90.   .  E  0.0  5.0  E-6  .3
      .3    93.   93.   .  E  .  E  C+
01003 5.  E-6  100.  97.   .  E  .2  1.1  E-6  .3
      .3    93.   93.   .  E  .  E  C+
01004 5.0  E-6  110.  103.  .  E  .9  1.8  E-6  .3
      .3    93.   8.0   .  E  .  E  C+

```


APPENDIX E.--SAMPLE INPUT WHEN ISEM = 1

Sample input data are listed when only pulse width versus power data on card set 5 are used.

APPENDIX E

.....
 1 2 3 4 5 6 7 8

1
 10IN3600 DIODE
 REVERSE FAILURE
 .800E-06 .110E+03
 .800E-06 .200E+03
 .900E-06 .900E+02
 .100E-06 .130E+03
 .120E-06 .900E+02
 .120E-06 .160E+03
 .180E-06 .930E+02
 .190E-06 .110E+03
 .220E-06 .600E+02
 .300E-06 .670E+02

2
 C-A FAIRCHILD
 PULSE WIDTH POWER

1 1
 R. PARSONS 7-23-73

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